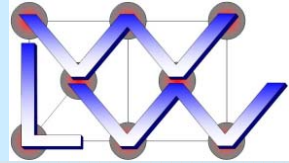


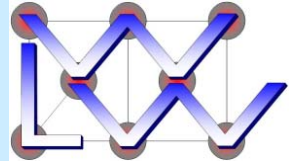
Markus Aicheler, Ruhr-University Bochum

*CLIC Material Fatigue Study:*  
**Thermal Fatigue Behavior versus Grain Orientation**

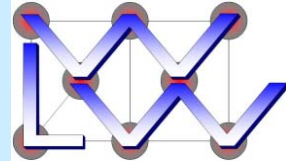


## Outline of the talk

- Motivation
- Observed material and tempers
- The 4 fatigue experiments
- Results and Discussion EBSD-Observation



1. Observe influence of crystallographic orientation on fatigue behavior
2. Show similarities between the different fatigue tests  
=> Show that the fatigue tests are coherent and relevant for CLIC structure!
3. Develop ideas how a good material against pulsed surface heating should look like



## C10100 (OFE Copper)

- Reference material
- Well known
- Results comparable to other researchers
- Supplementary fatigue data needed (CuZr already well tested by Samuli)

## 40% cold worked

- as received
- Round bar cold rolled  $\varnothing$  40 mm and  $\varnothing$  100 mm
- Yield Strength:  $R_{p0.2} = 316$  MPa
- Ultimate tensile strength:  $R_m = 323$  MPa
- Average grain size:  $\varnothing$  110  $\mu$ m

## Brazed

- Heat treatment in vacuum furnace:  
300 K/h  $\rightarrow$  795  $^{\circ}$ C; 60 min hold  
100 K/h  $\rightarrow$  825  $^{\circ}$ C; 6 min hold  
Natural cooling in vacuum
- Yield Strength:  $R_{p0.2} \approx 72$  MPa
- Ultimate tensile strength:  $R_m = 270$  MPa
- Average grain size:  $\varnothing$  400  $\mu$ m

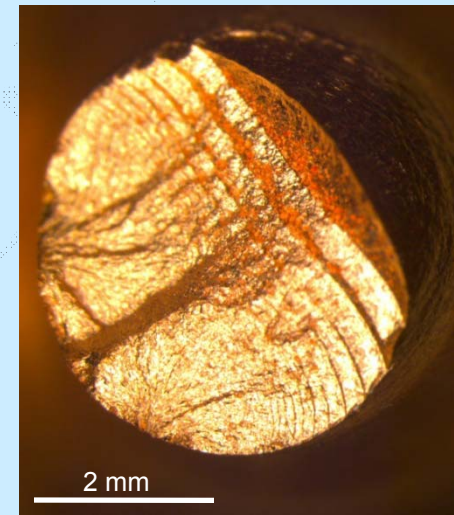
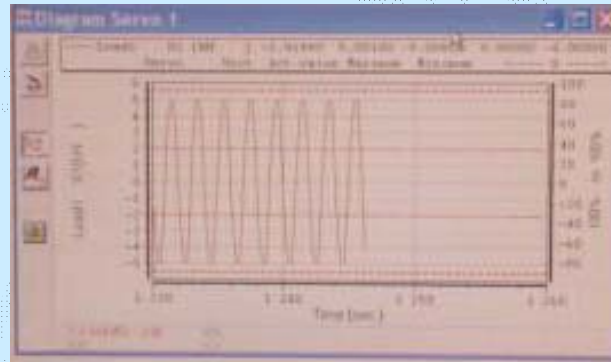
## 2h@1000 $^{\circ}$ C

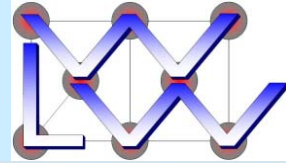
- Heat treatment in vacuum furnace:  
300 K/h  $\rightarrow$  1000  $^{\circ}$ C; 120 min hold  
Natural cooling in vacuum
- Yield Strength:  $R_{p0.2} \approx 72$  MPa
- Ultimate tensile strength:  $R_m = 257$  MPa
- Average grain size:  $\varnothing$  1400  $\mu$ m

# Conventional fatigue test



- Mechanical fatigue;  $R = -1$  ( $R = \sigma_{\max} / \sigma_{\min}$ )
- UTS electro-mechanical universal-test machine
- Repetition rate 0.5 Hz
- Load +/-220 MPa; stress controlled
- Sample shape conform ISO 12106
- 3-5 samples for one data point
- Damage criterion: rupture

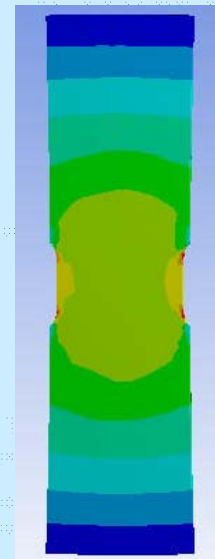




- Mechanical fatigue;  $R = -1$  ( $R = \sigma_{\max} / \sigma_{\min}$ )
- Piezo electric resonant attenuator
- Repetition rate 24 kHz
- Load +/-70 MPa; strain controlled
- 3-5 samples for one data point
- Damage criterion: roughness or crack

## New sample shape:

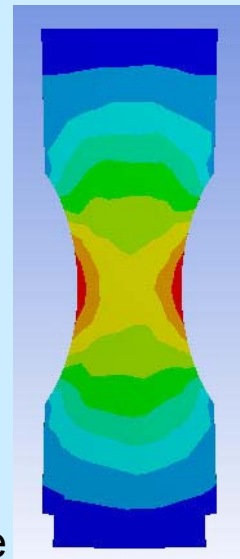
- easier surface observation & replica
- one defined gage length
- easier to machine & electro polish
- comparison to results of other researchers

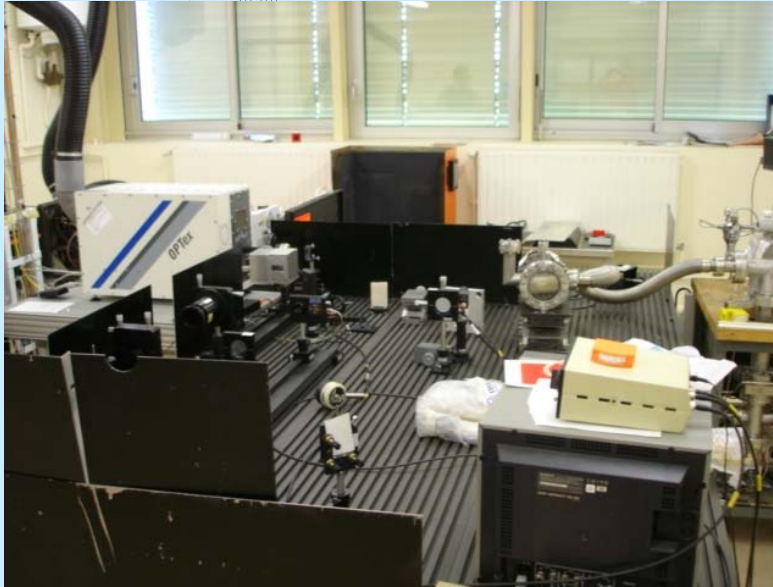
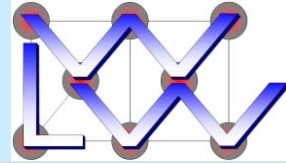


Former shape

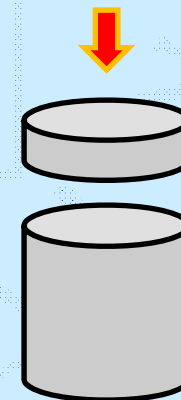


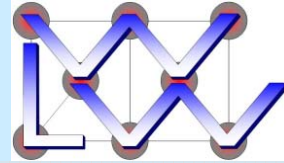
New shape





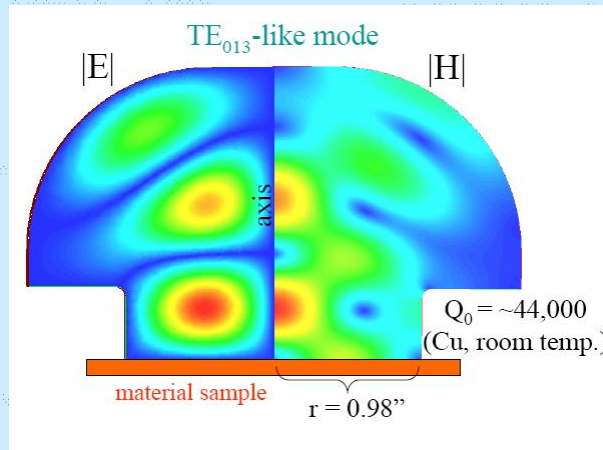
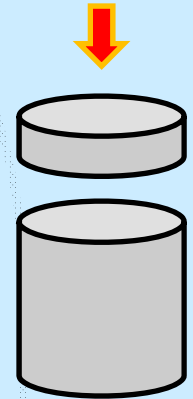
- Thermal fatigue in vacuum
- OPTEX Excimer Laser;  $\lambda = 248 \text{ nm}$
- Repetition rate 200 Hz
- $5 \times 10^4$  shots @  $0.3 \text{ J/cm}^2 \approx \Delta T 250 \text{ }^\circ\text{C}$
- Round disc diameter 40 mm
- 25 discrete spots per disc
- Damage criterion: Roughness





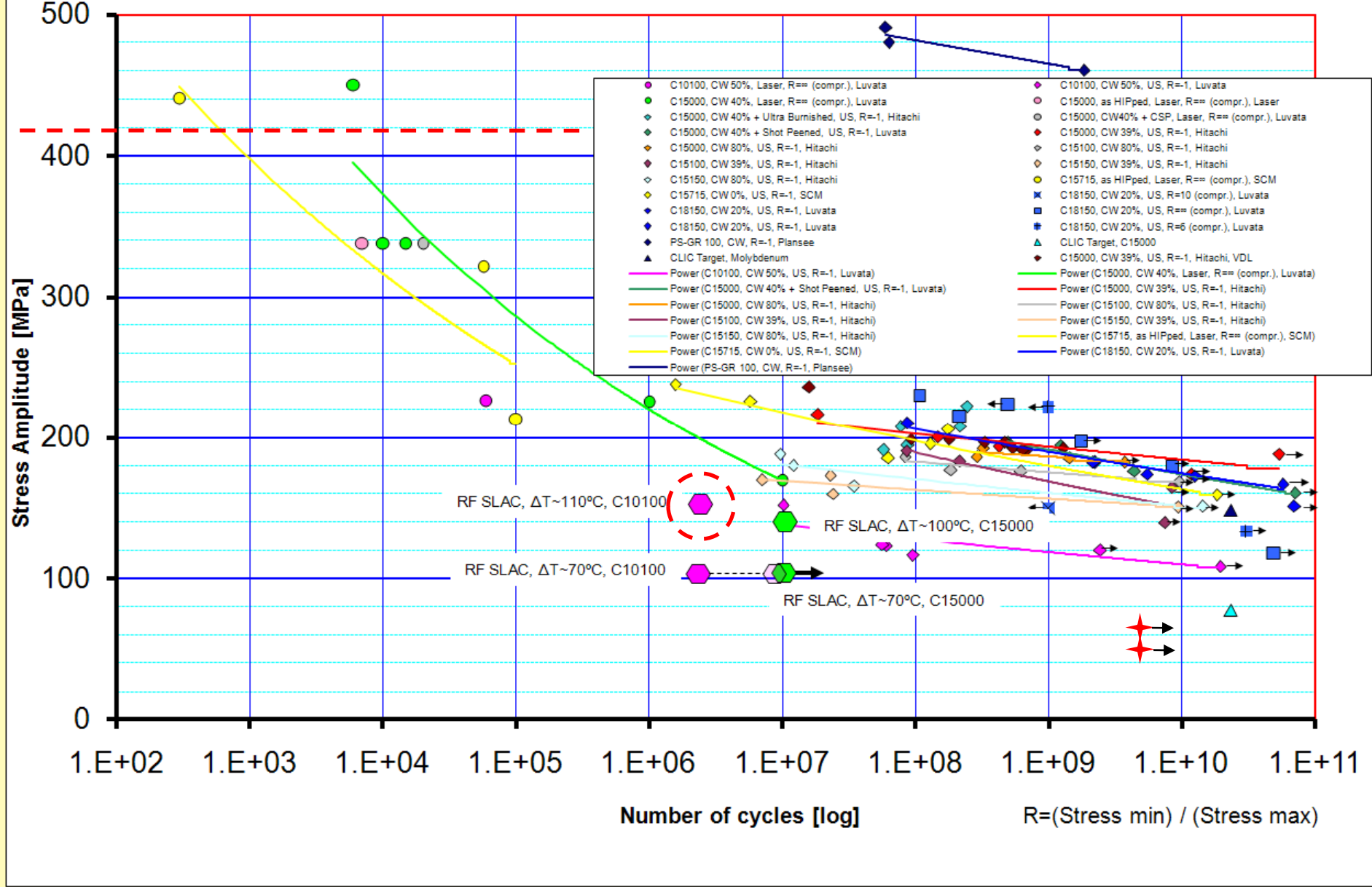
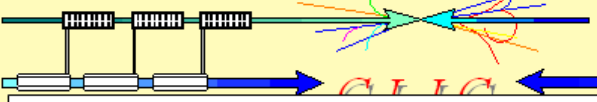
Photos: Sami Tantawi  
Presentation 23 Jan. 2008

- Thermal fatigue due to RF heating
- Mushroom cavity @ 11,4 GHz
- Repetition rate 50 Hz
- $2 \times 10^6$  Pulses;  $\Delta T_{\max}$  110 °C
- Round disc diameter 100 mm
- Continuous radial distribution of  $\Delta T$
- Damage criterion ?





# Wöhler curves of the test results (Stress vs. N)



# Observation techniques used: EBSD

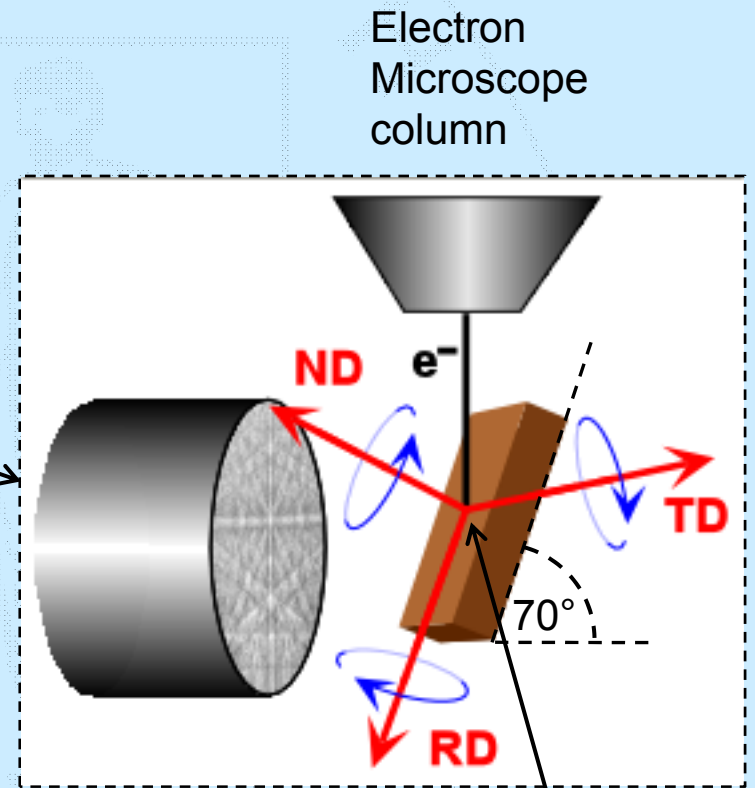
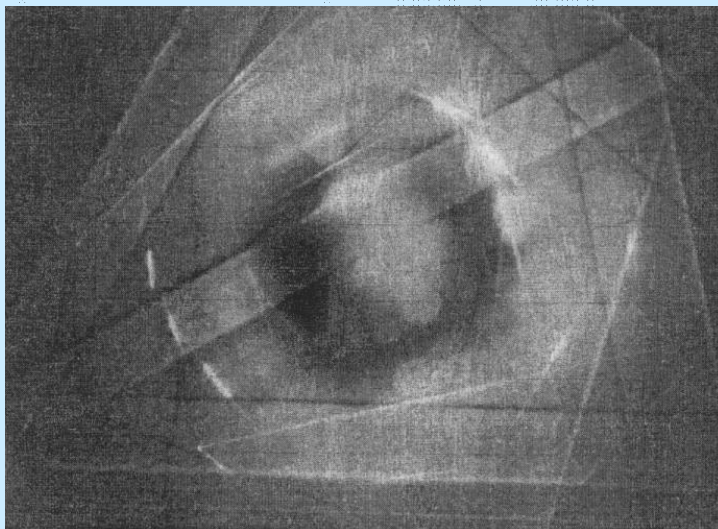
## Electron Back Scattered Diffraction

SEM: Leo 1530 VP

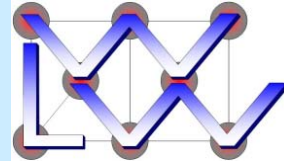
EBSD unit: EDAX TSL

Phosphoric screen and digital camera

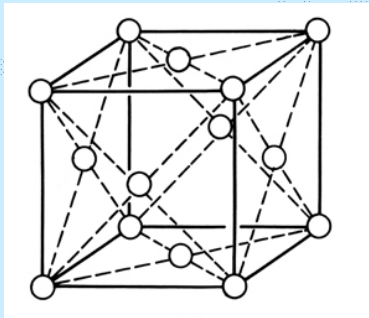
Kikuchi pattern



“Bragg Reflection”

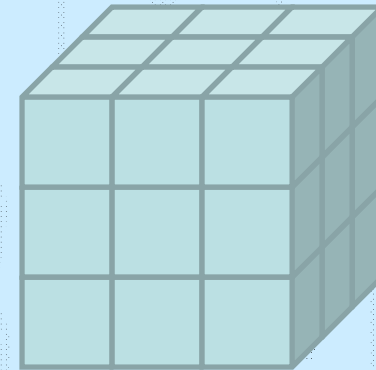


A cube with atoms on its corners and its faces (so called face centered cubic FCC)

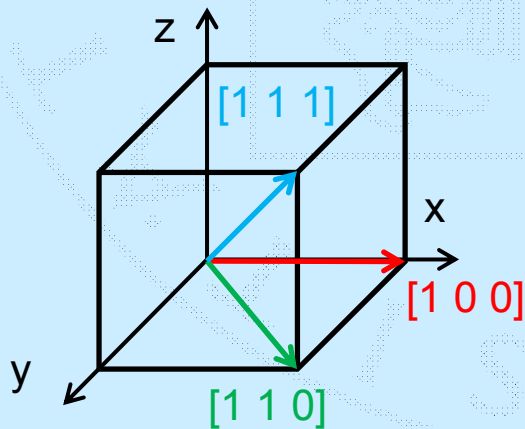


(elementary cell)

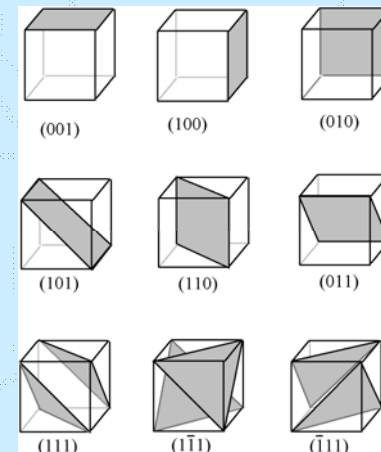
Plenty of these elementary cells



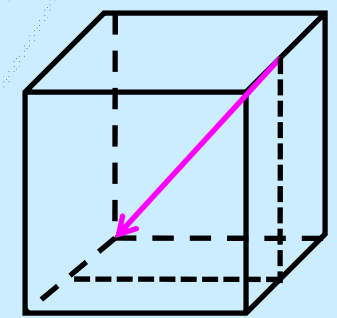
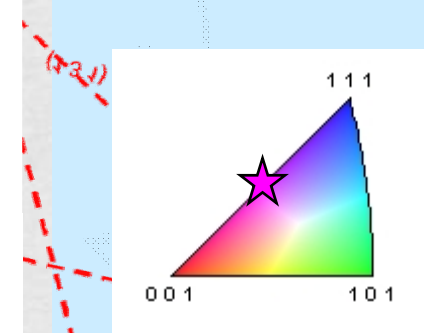
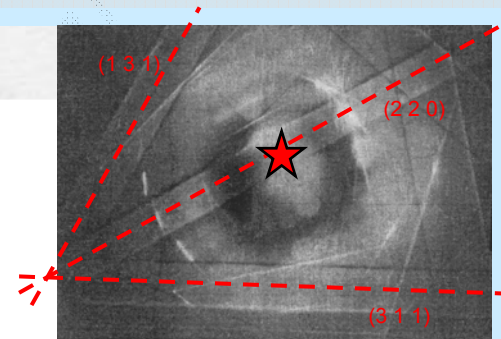
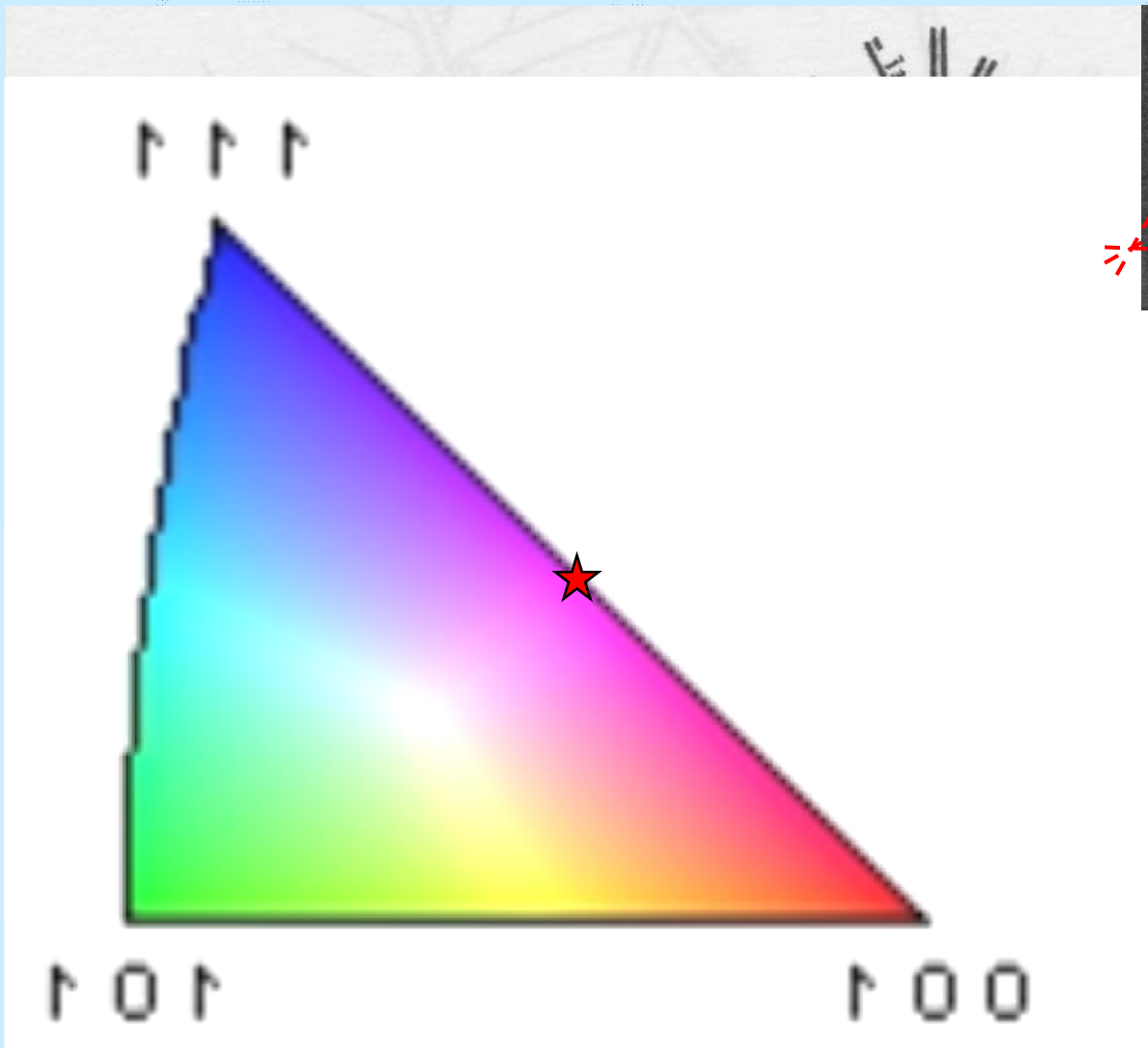
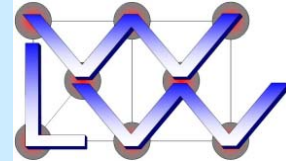
Crystallographic description of directions:

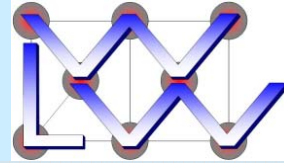


Crystallographic description of planes:  
Normal vector of planes!



# Kikuchi line indexing





Scan:

Each point one Kikuchi pattern

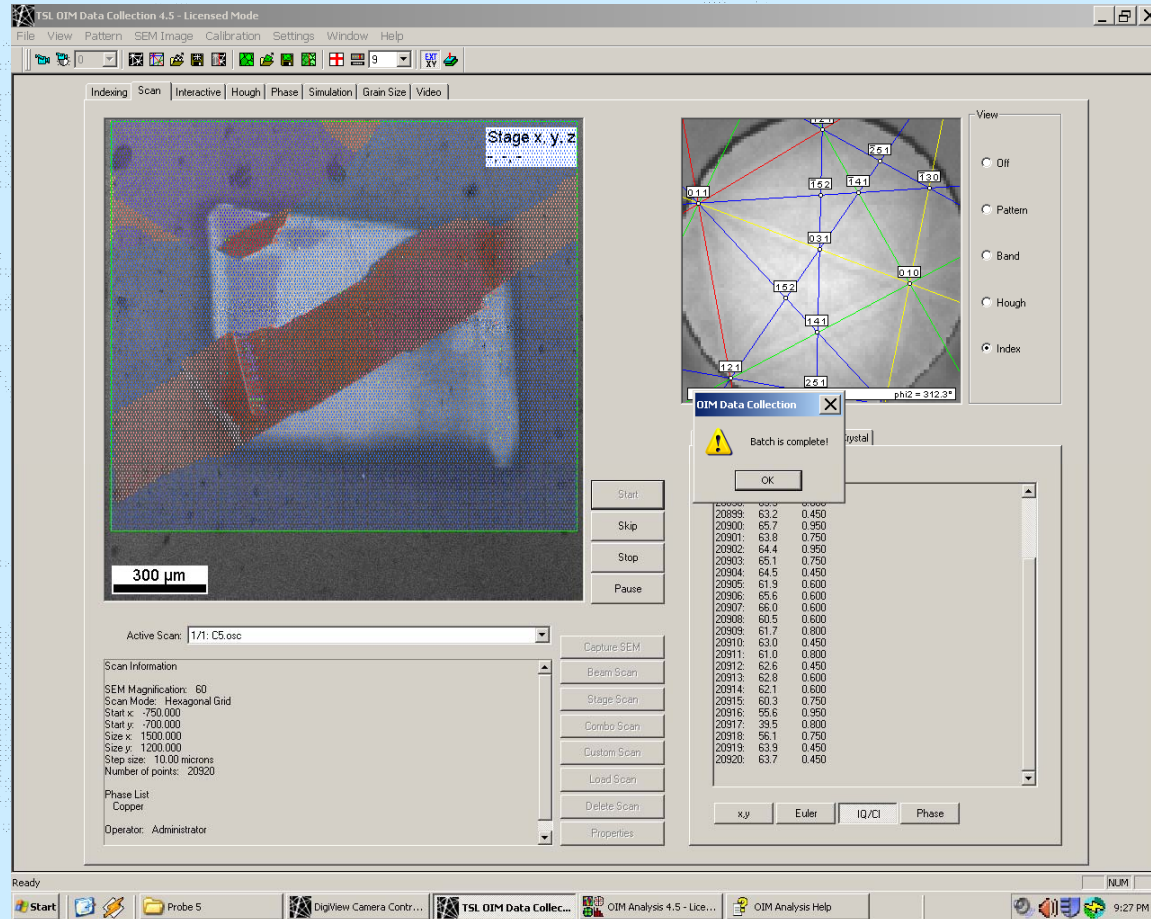
-> each point complete orientation information

=> Mapping of orientations

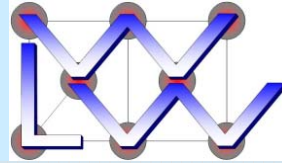
Scan rate: 75 points/s

Ordinary used for:

- Texture analysis
- Orientation of samples (like X-Ray diffraction but faster)
- Identification of different phases (like TEM but lower resolution/magnification)
- Possibility to connect with quantitative EDX scans



# SLAC Virgin Surface



Mag = 200 X

EHT = 20.00 kV

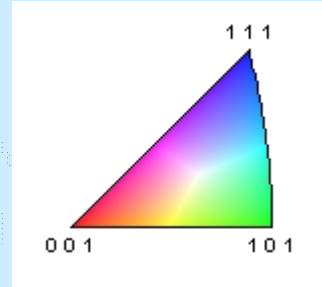
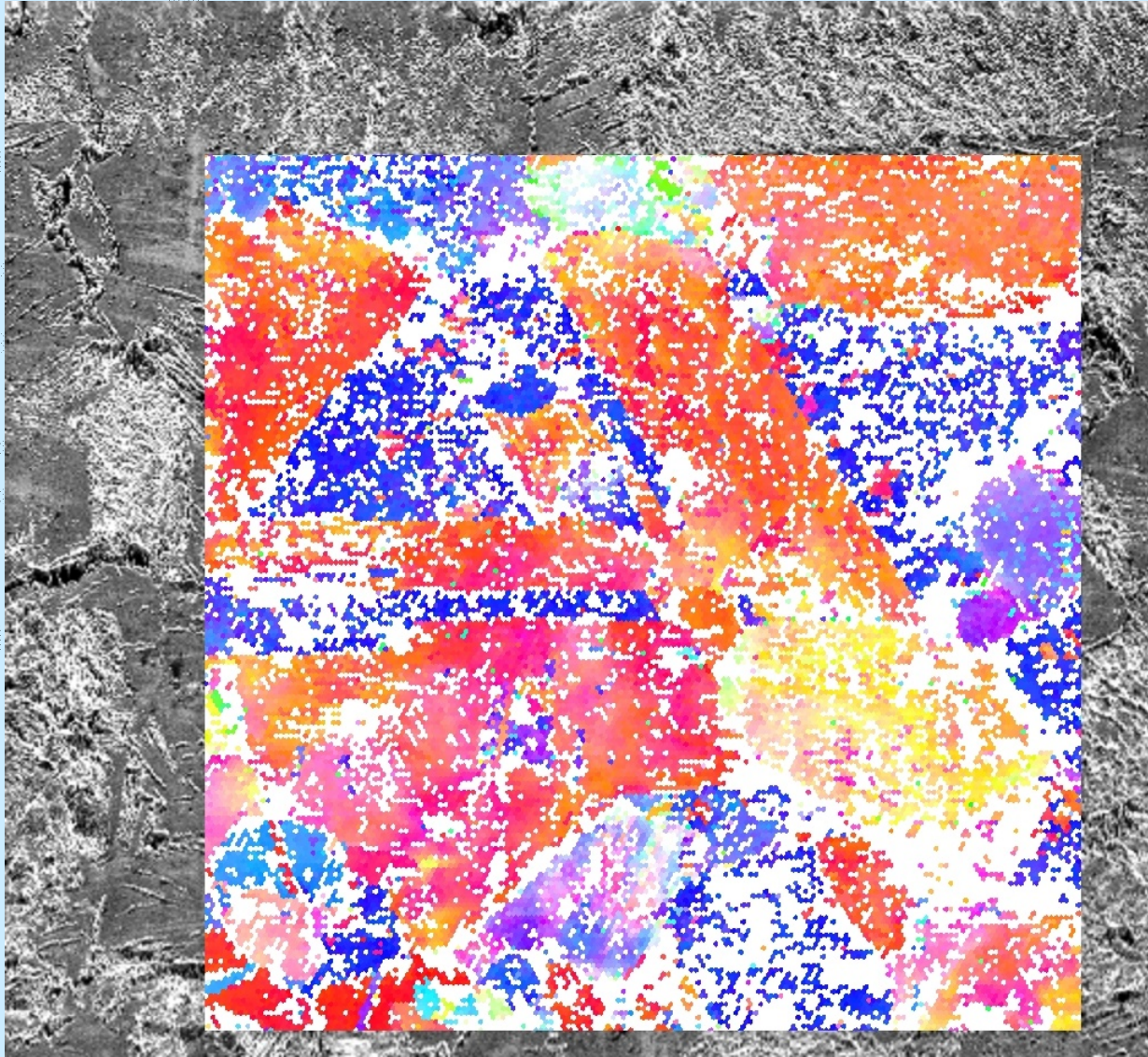
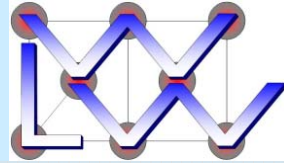
100µm

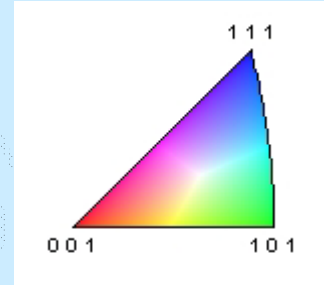
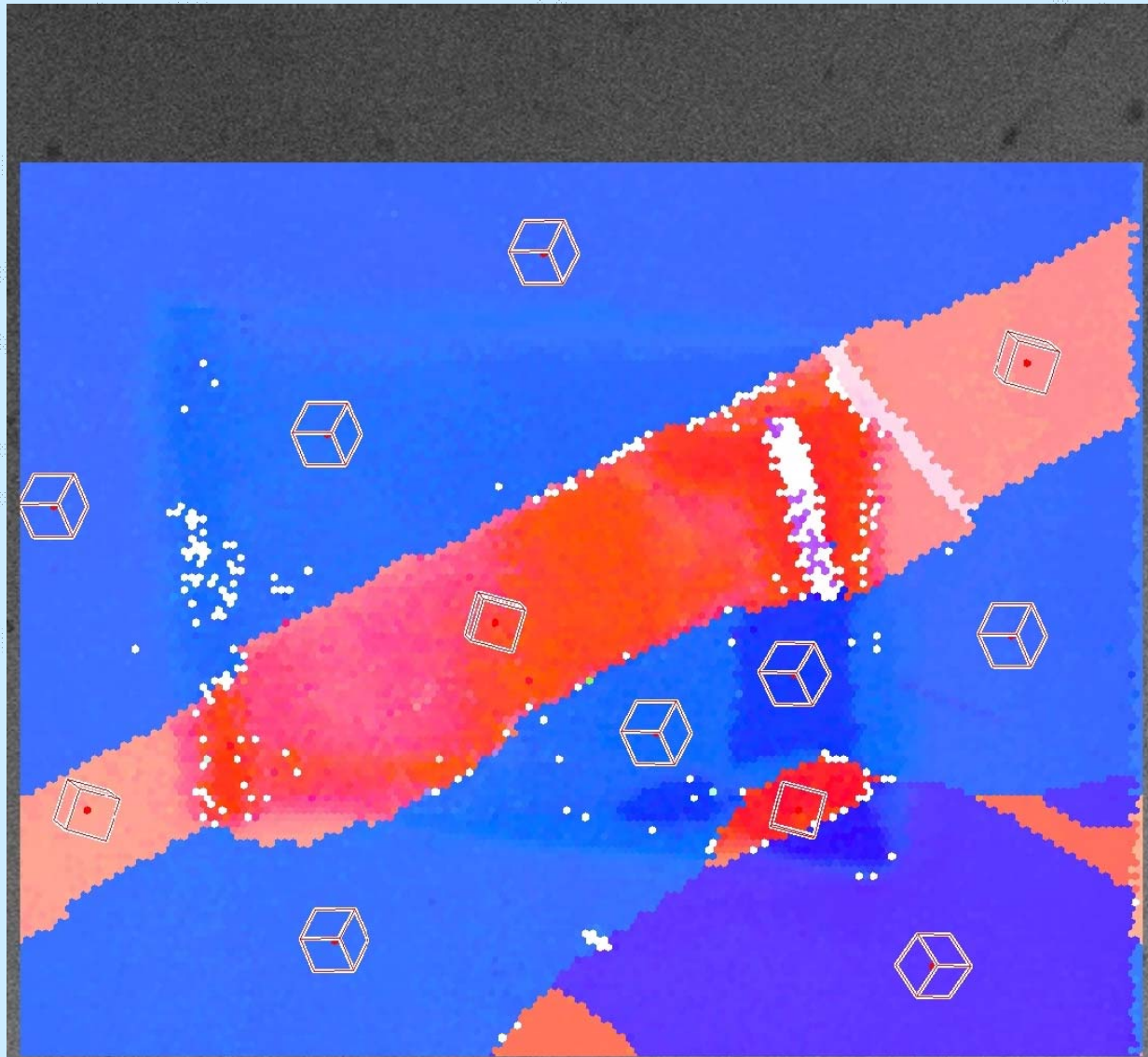
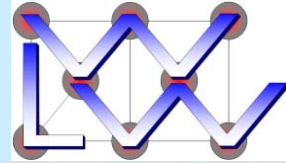


C10100-SLAC

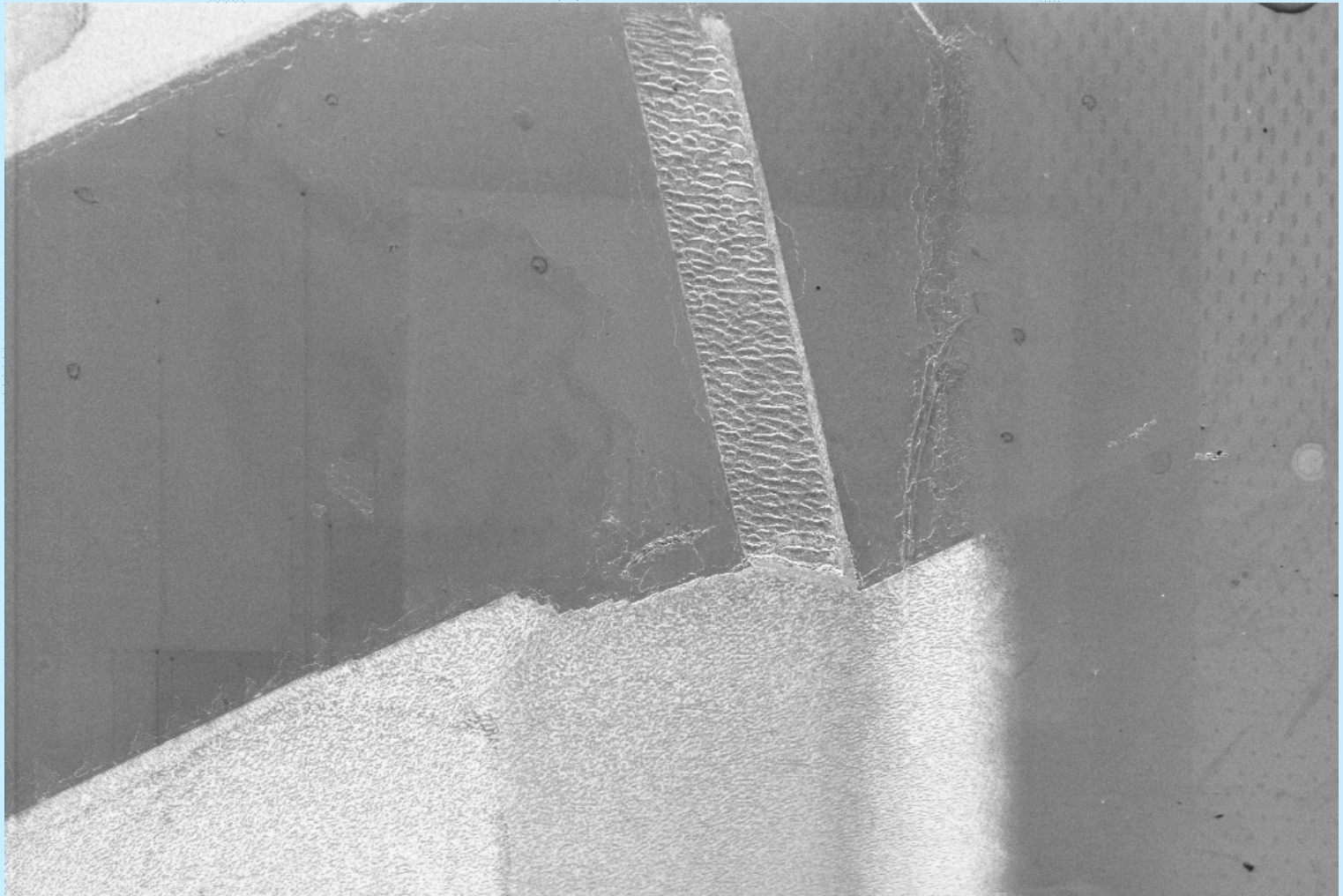
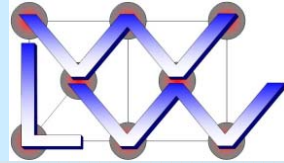
Detector = SE1

Date :13 Aug 2008









Mag = 200 X

EHT = 20.00 kV

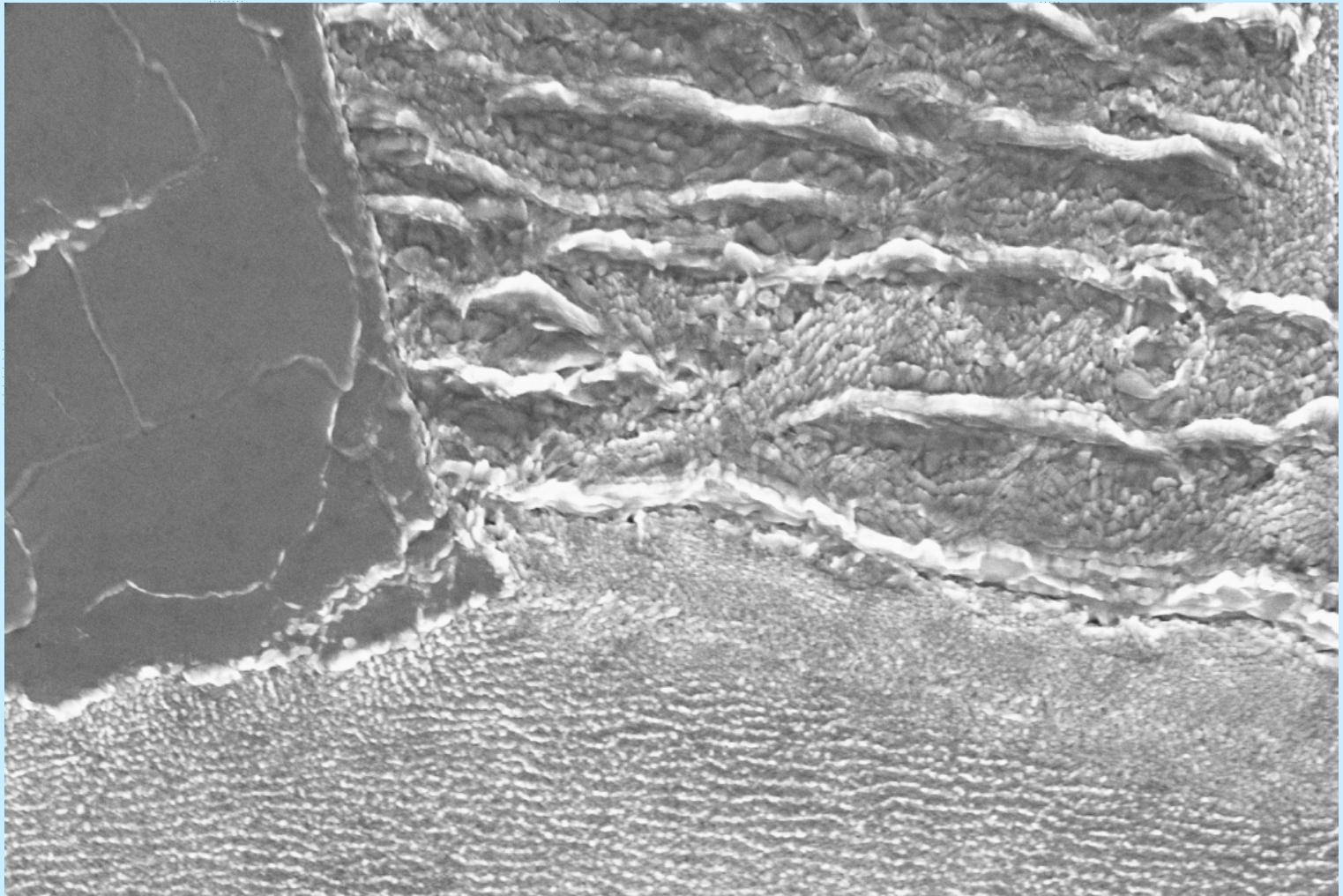
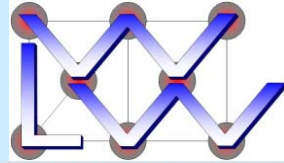
100µm



C10100\_2h1000\_EP\_Pr5\_C5

Detector = SE1

Date :13 Aug 2008



Mag = 2.00 K X

EHT = 20.00 kV

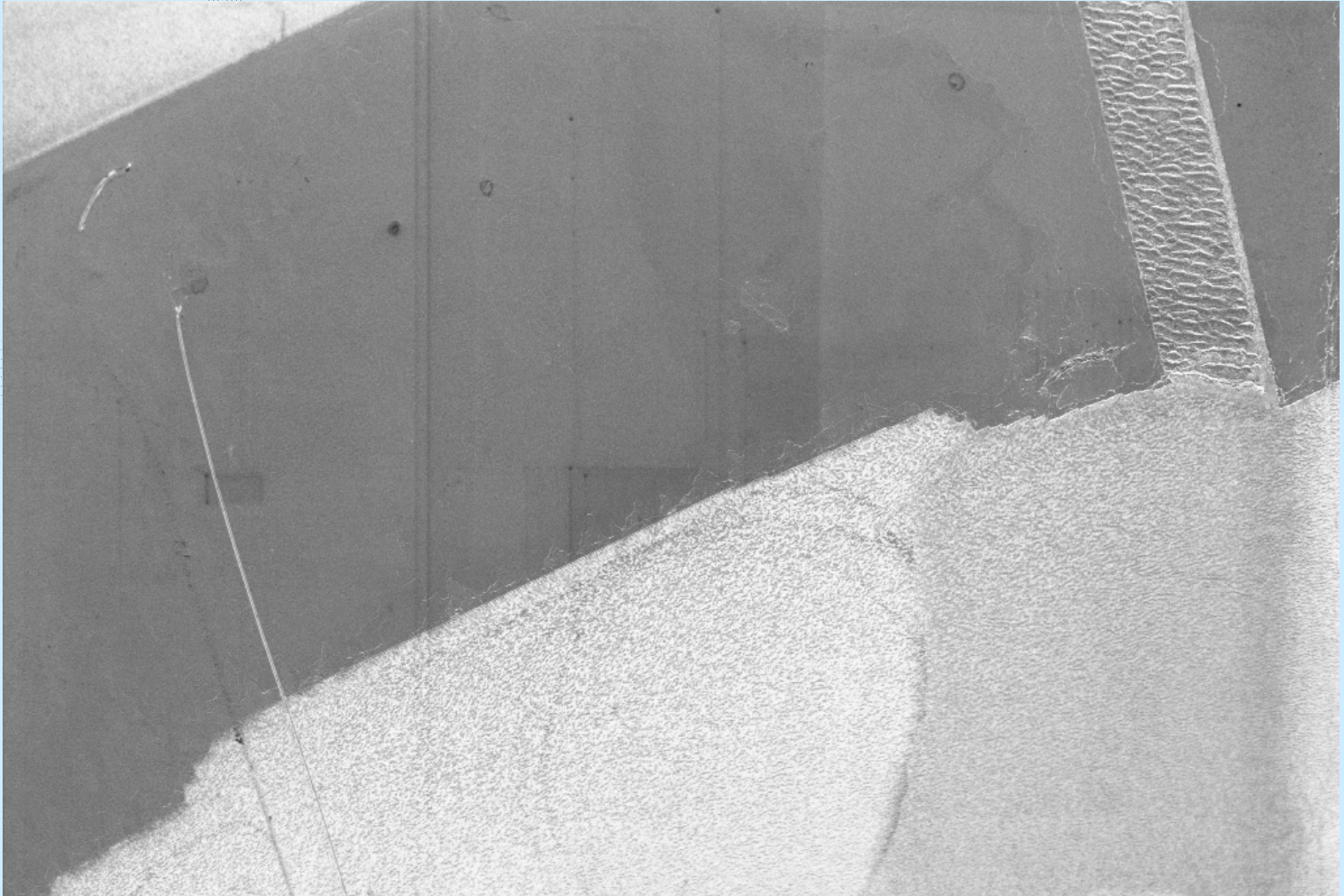
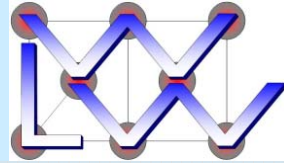
10µm



C10100\_2h1000\_EP\_Pr5\_C5

Detector = SE1

Date :13 Aug 2008



Mag = 200 X

EHT = 20.00 kV

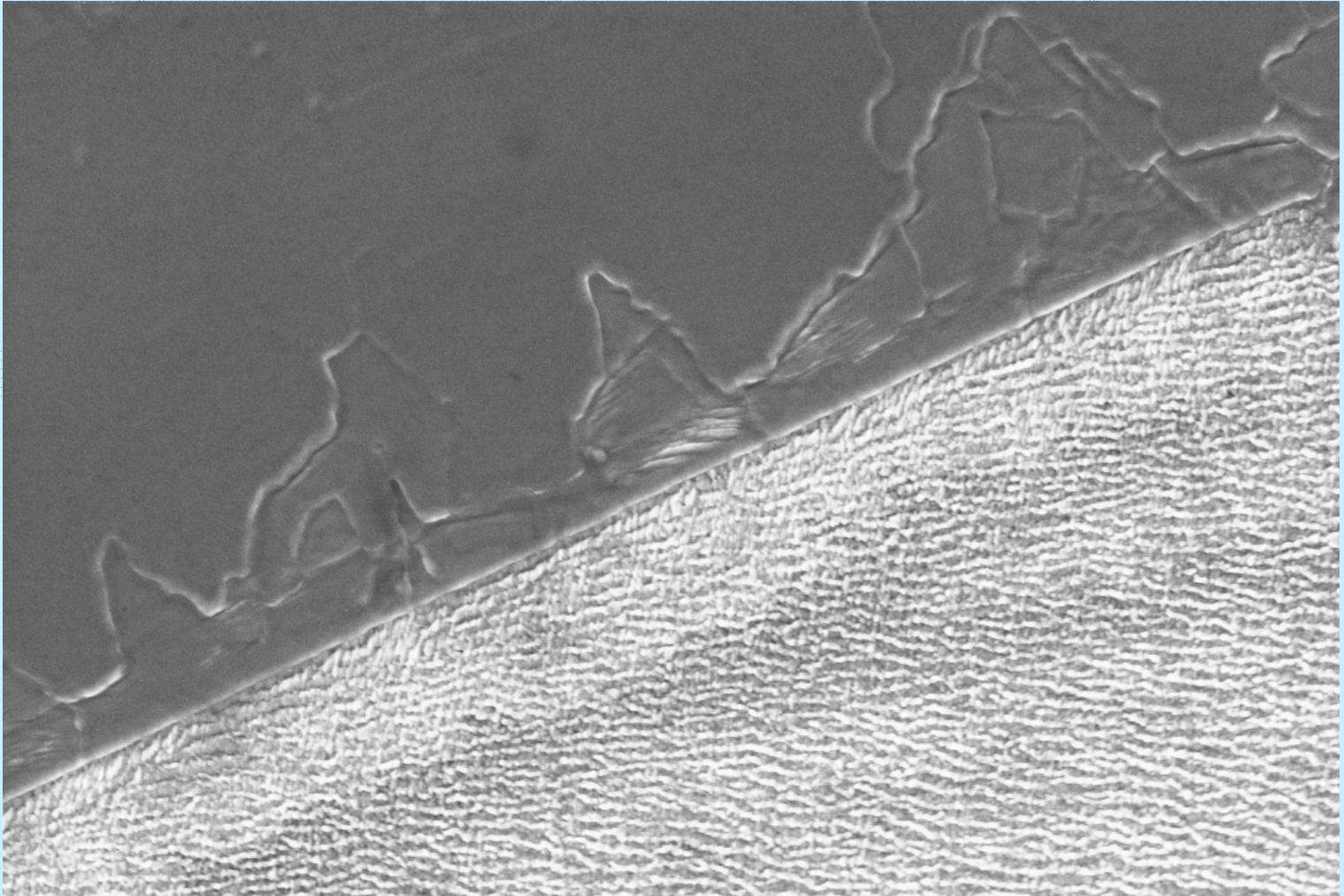
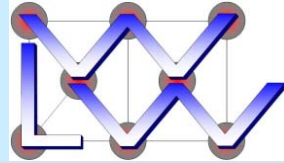
100µm



C10100\_2h1000\_EP\_Pr5\_C5

Detector = SE1

Date :13 Aug 2008



Mag = 2.00 K X

EHT = 20.00 kV

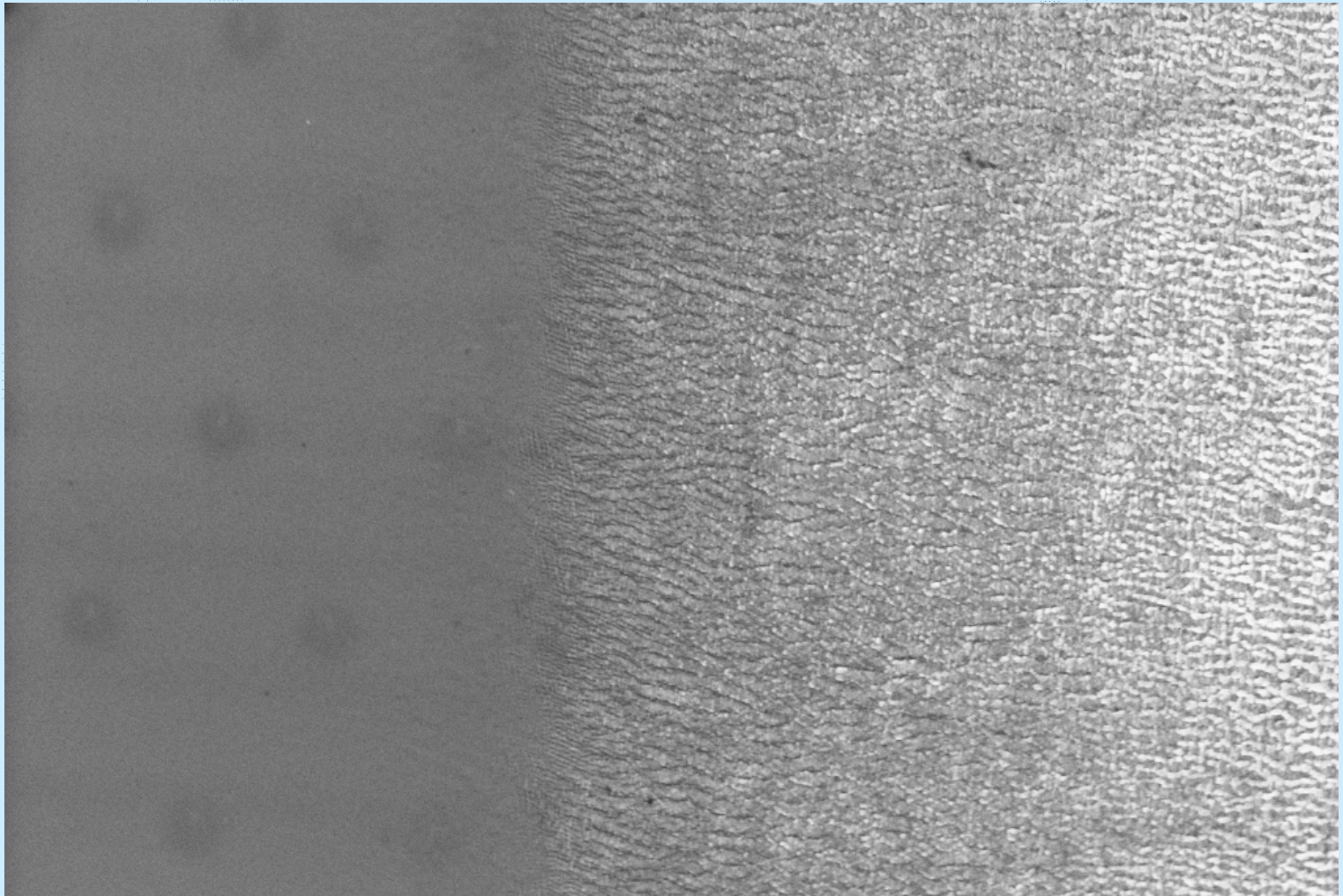
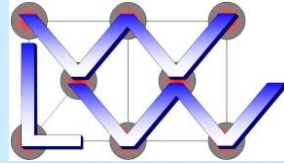
10µm



C10100\_2h1000\_EP\_Pr5\_C5

Detector = SE1

Date :13 Aug 2008



Mag = 2.00 K X

EHT = 20.00 kV

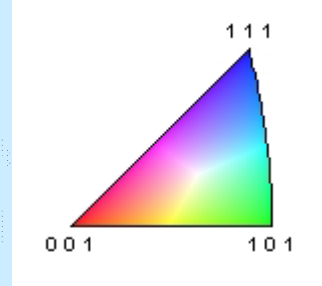
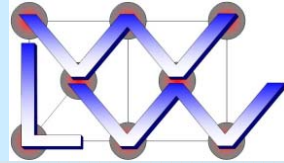
10µm

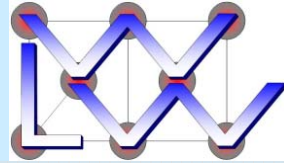


C10100\_2h1000\_EP\_Pr5\_C5

Detector = SE1

Date :13 Aug 2008





Mag = 200 X

EHT = 20.00 kV

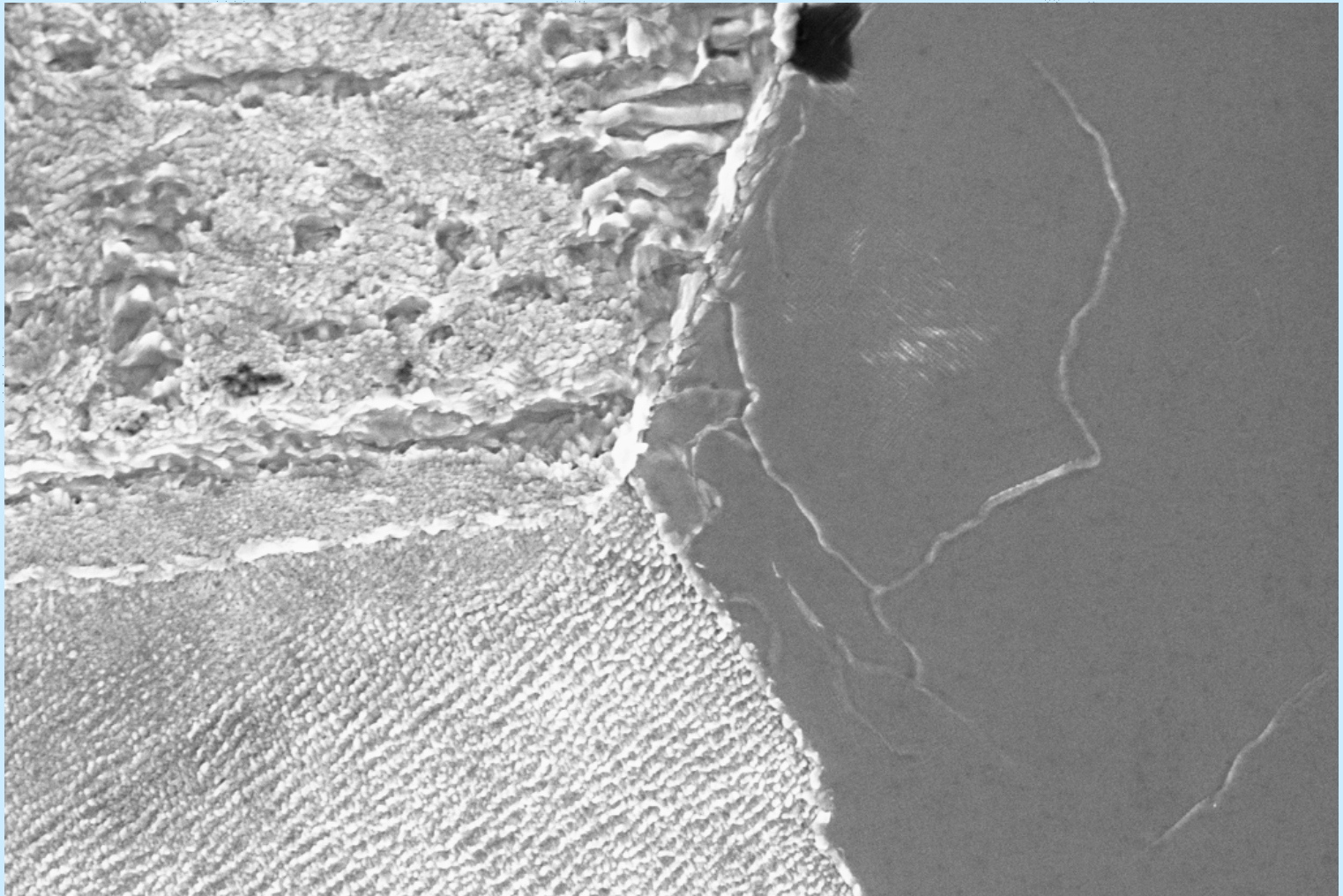
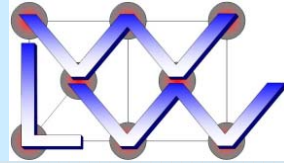
100µm



C10100\_2h1000\_EP\_Pr5\_D4

Detector = SE1

Date :13 Aug 2008



Mag = 2.00 K X

EHT = 20.00 kV

10µm

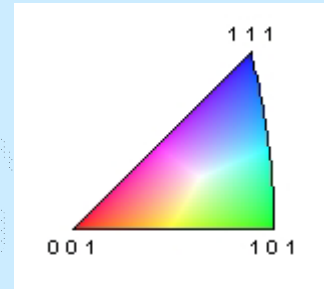
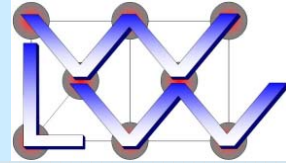


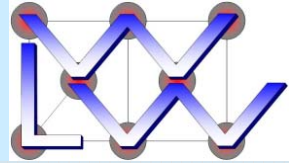
C10100\_2h1000\_EP\_Pr5\_D4

Detector = SE1

Date :13 Aug 2008







Mag = 200 X

EHT = 20.00 kV

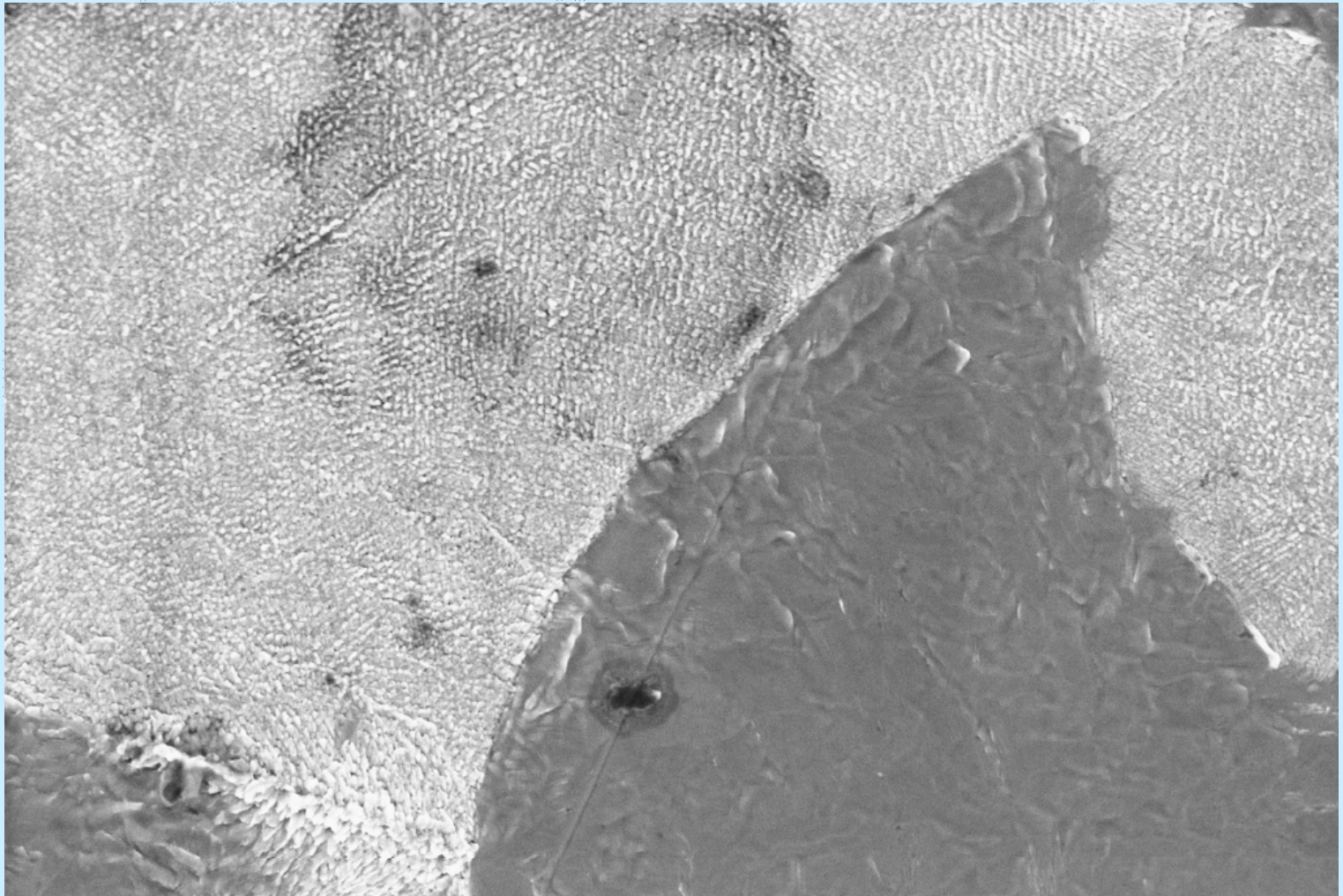
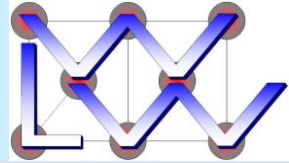
100µm



C10100-40CW-EP\_A1

Detector = SE1

Date :13 Aug 2008



Mag = 2.00 K X

EHT = 20.00 kV

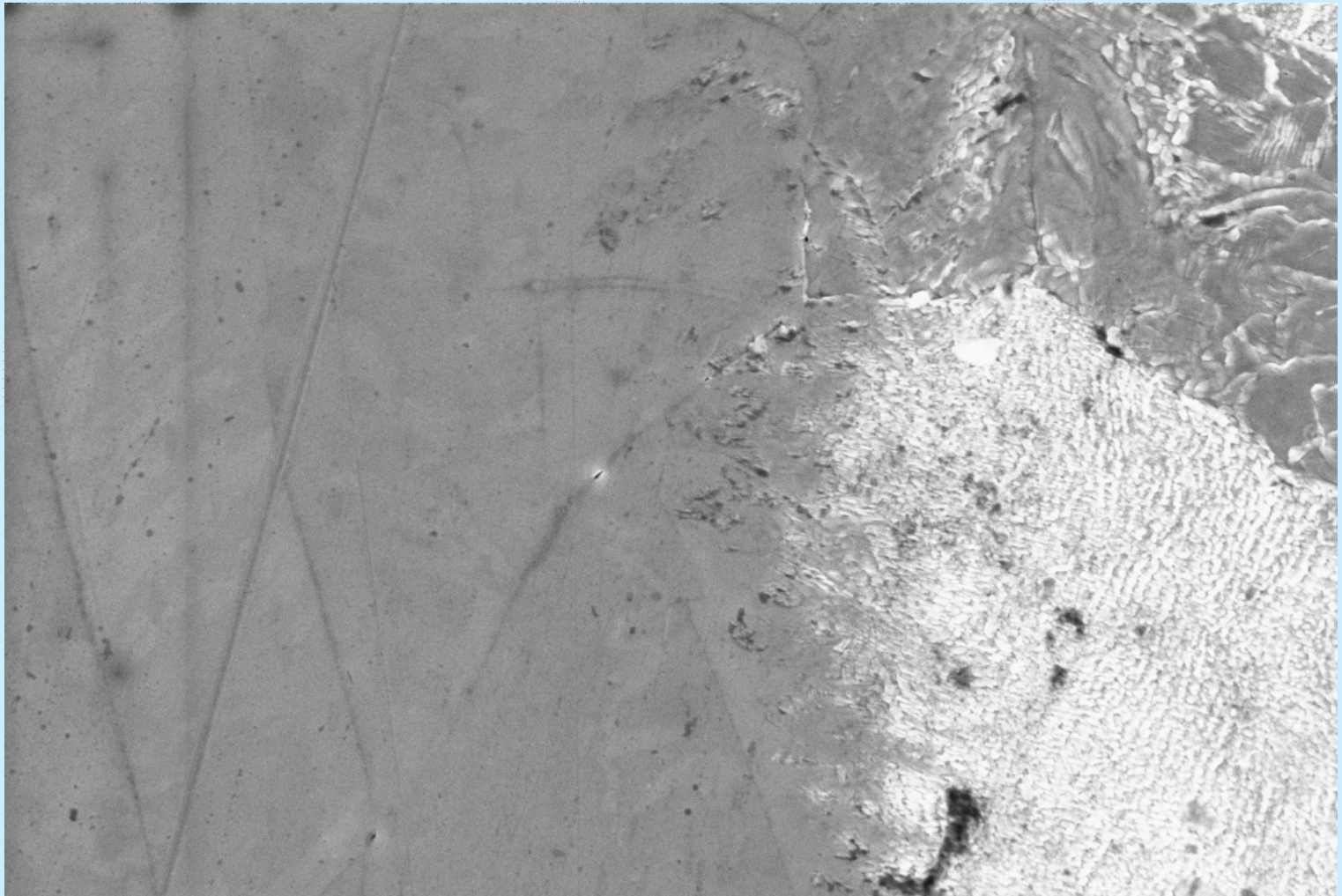
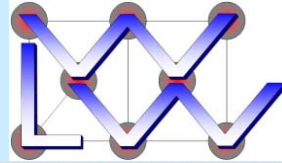
10µm



C10100-40CW-EP\_A1

Detector = SE1

Date :13 Aug 2008



Mag = 2.00 K X

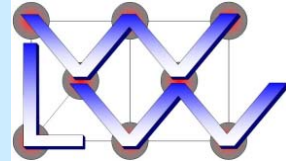
EHT = 20.00 kV

20µm

C10100-40CW-EP\_A1

Detector = SE1

Date :13 Aug 2008



- [1 1 1] (blue) direction high developed and [1 0 0] (red) direction less developed fatigue features

-> evidence of influence of orientation on fatigue behaviour

-> One reason: Isotropic thermal expansion causes due to anisotropic module different stresses ( $\sigma_{[111]}/\sigma_{[100]} = 2.3$  !!!)

=> fatigue samples of different orientation

=> quantify surface fatigue damage <-> orientation

- Orientation <-> fatigue behaviour same trend in RF-fatigue as well as in Laser fatigue!

-> additional hint for equality of fatigue techniques

=> proof the same behaviour for the ultrasound-device

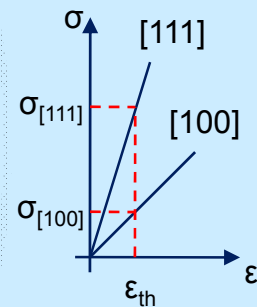
- [1 1 1] (blue) direction dominating after extreme heat treatment

-> preferred and less preferred orientations

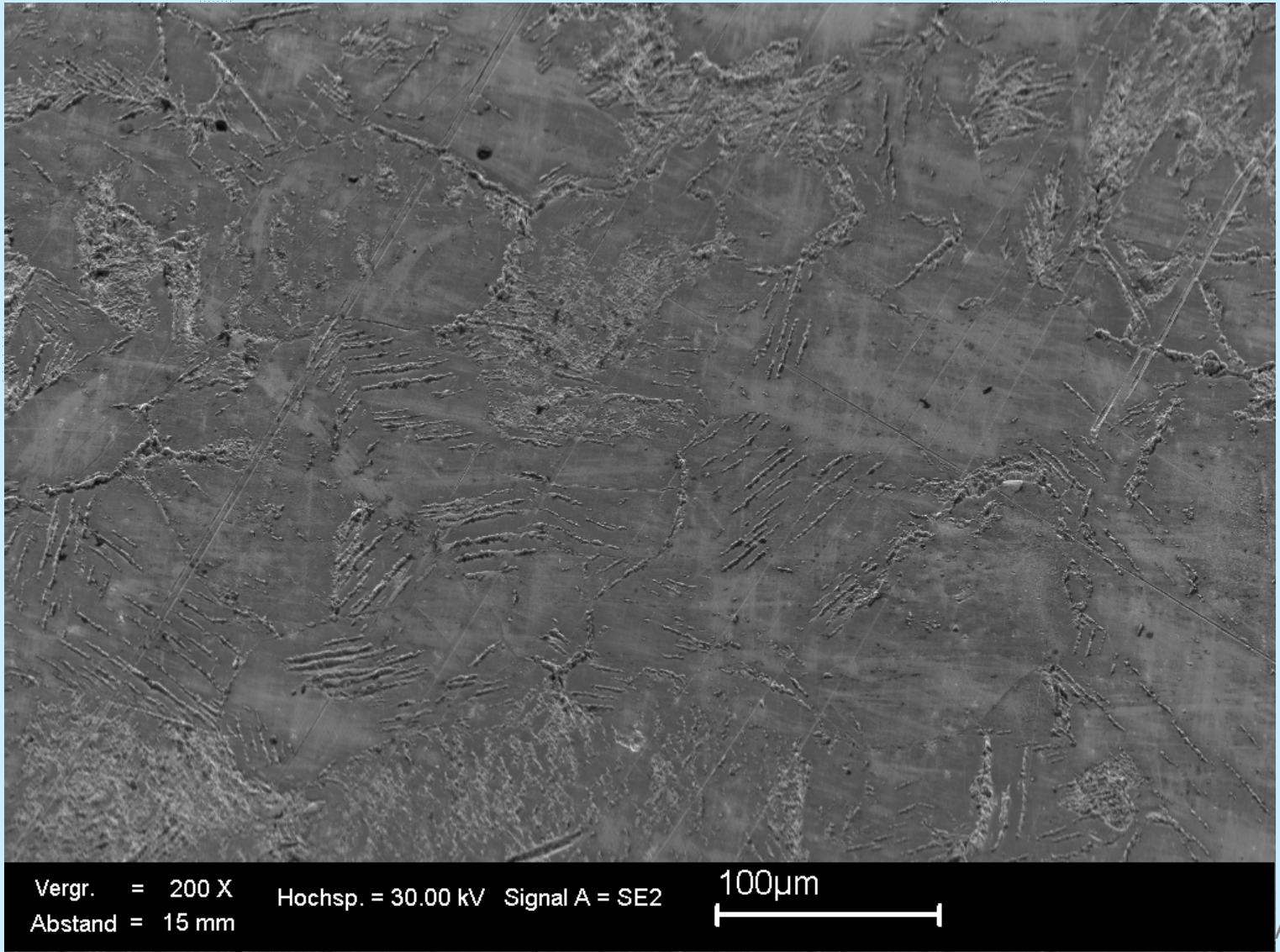
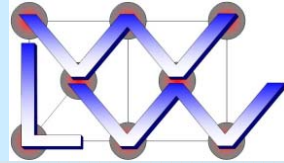
-> texture already exists in raw material

-> further texture development through thermal treatment

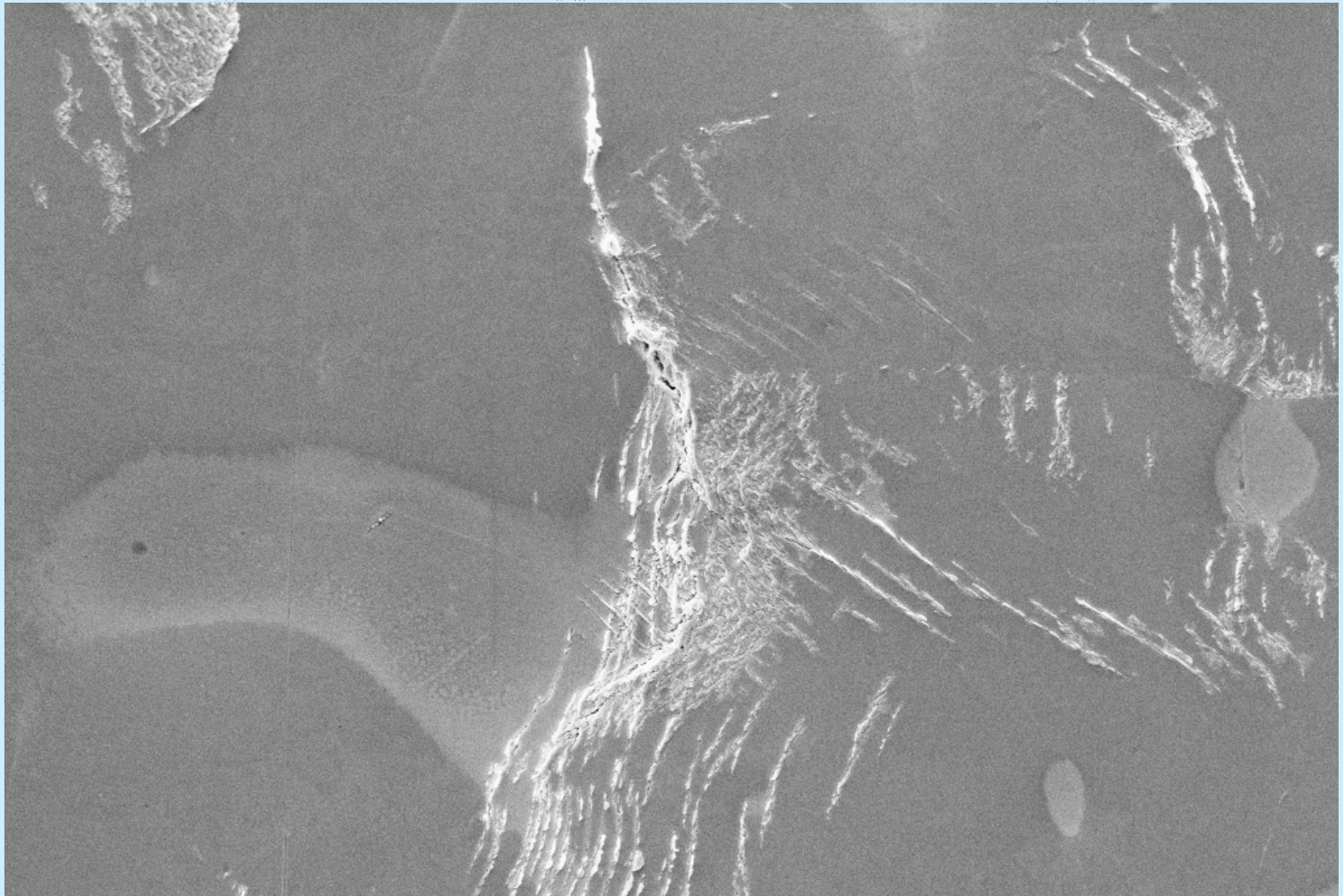
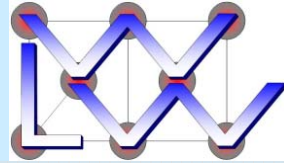
=> Need for further observation upon the influence of textures



# Recent Picture: SLAC sample



# Recent Picture: Ultra sound sample



Mag = 500 X

EHT = 20.00 kV

20µm

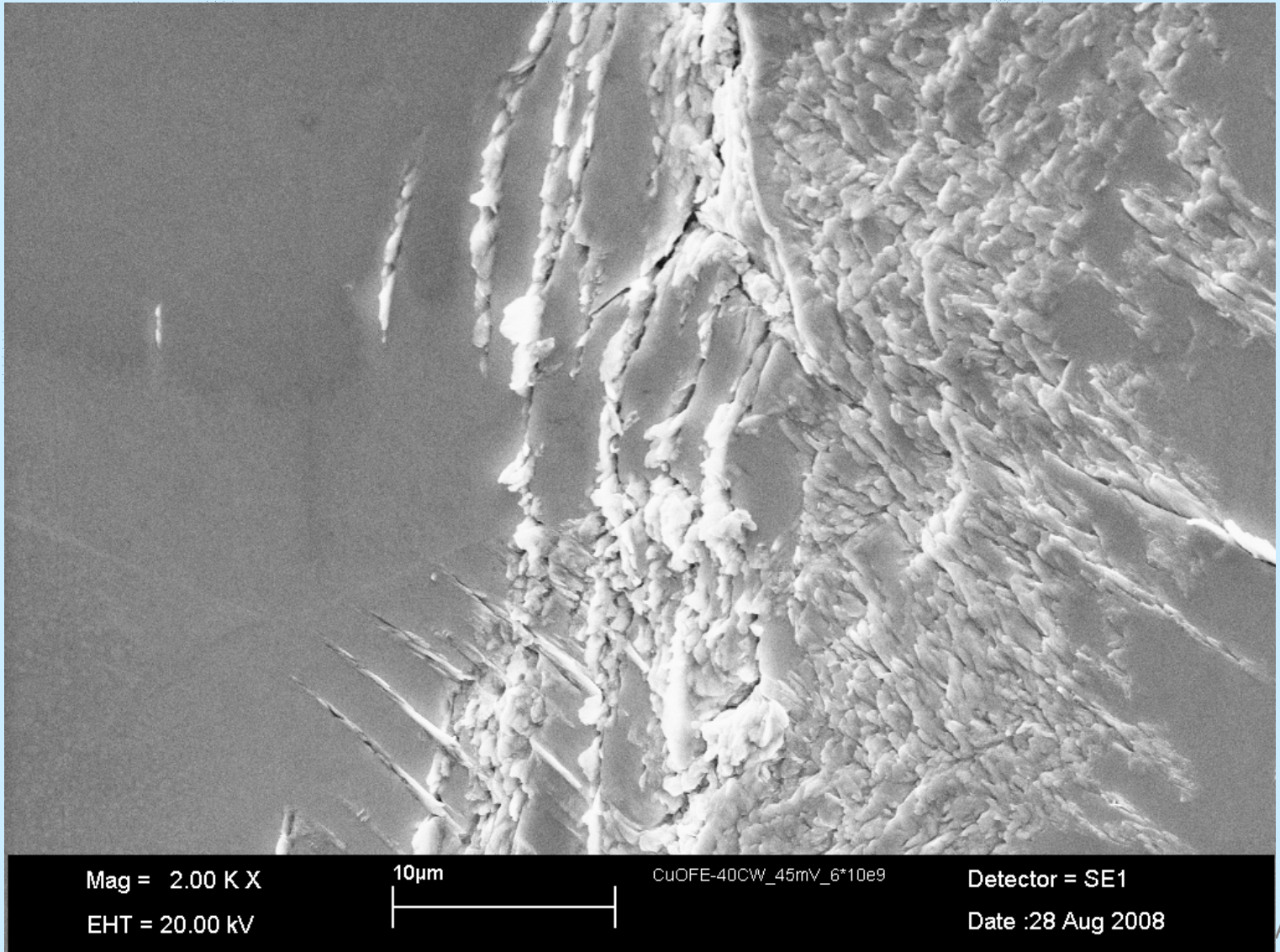
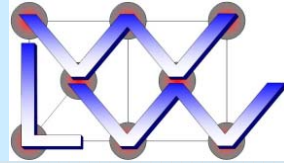


CuOFE-40CW\_45mV\_6\*10e9

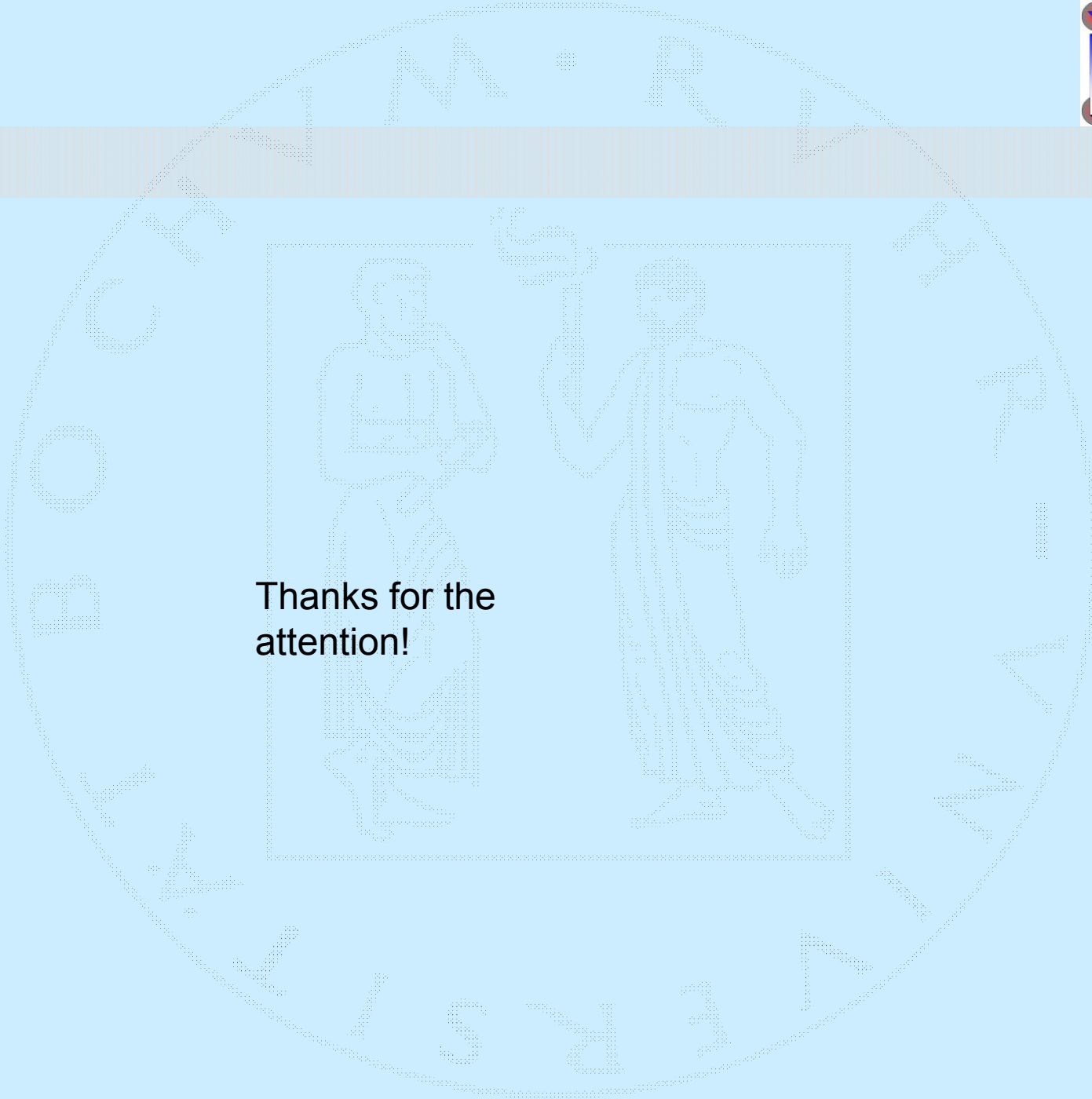
Detector = SE1

Date :28 Aug 2008

# Recent Picture: Ultra sound sample







Thanks for the  
attention!

# Observation techniques used: EBSD

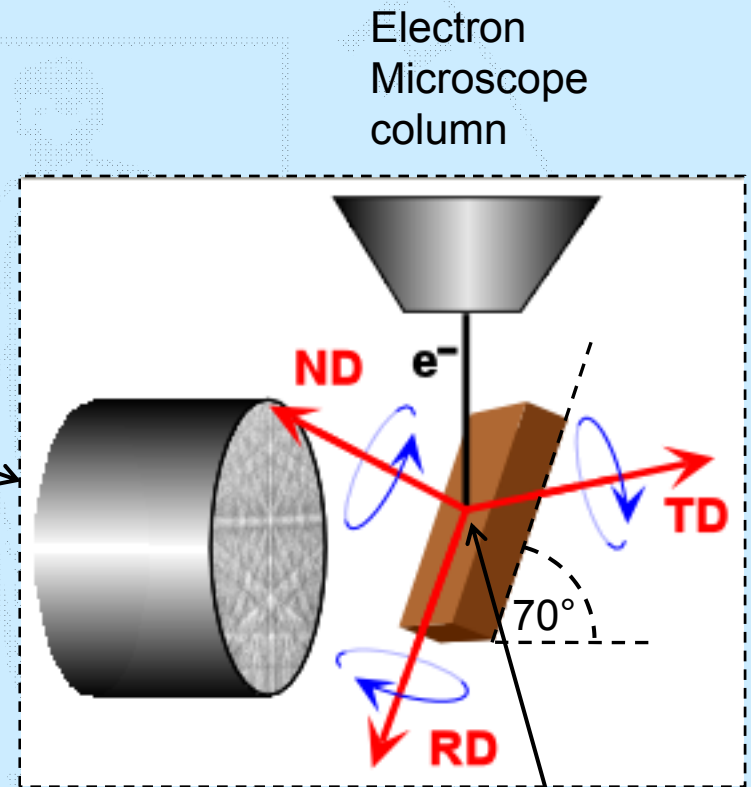
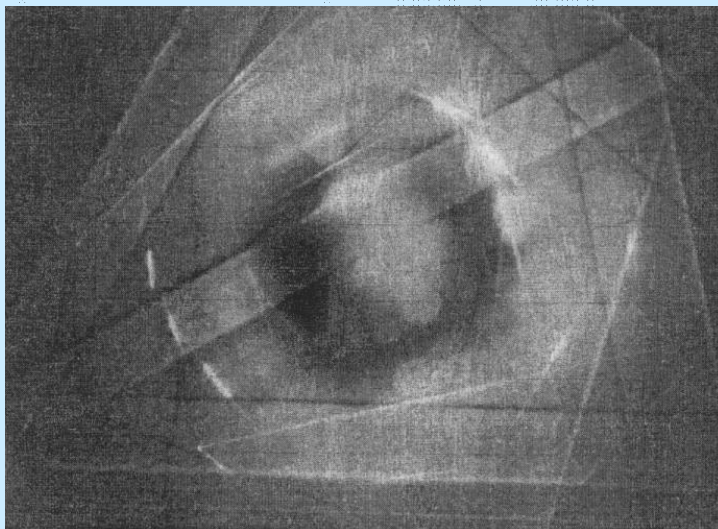
## Electron Back Scattered Diffraction

SEM: Leo 1530 VP

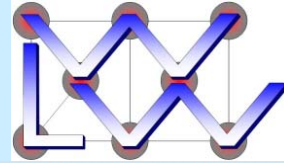
EBSD unit: EDAX TSL

Phosphoric screen and digital camera

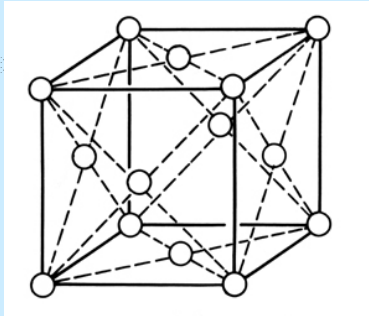
Kikuchi pattern



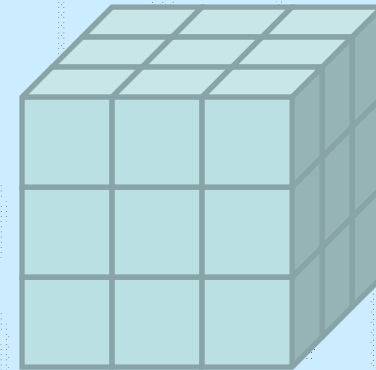
“Bragg Reflection”



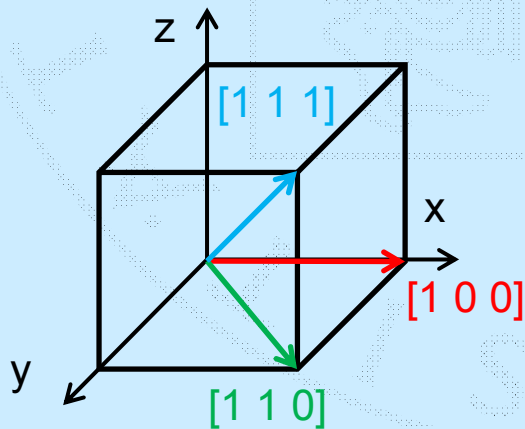
A cube with atoms on its corners and its faces (so called face centered cubic FCC)



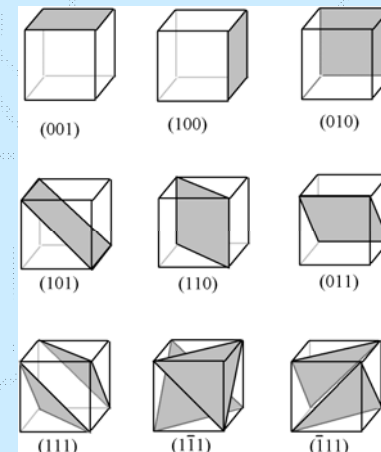
Plenty of these elementary cells



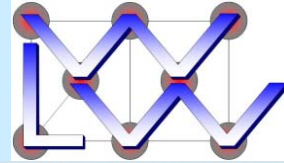
Crystallographic description of directions:



Crystallographic description of planes:  
Normal of planes!



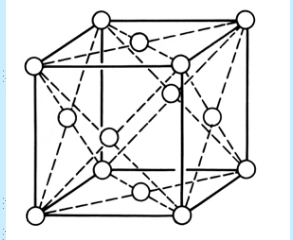
# Basics for EBSD: Bragg Reflection



$I_0$ : intensity of initial ray

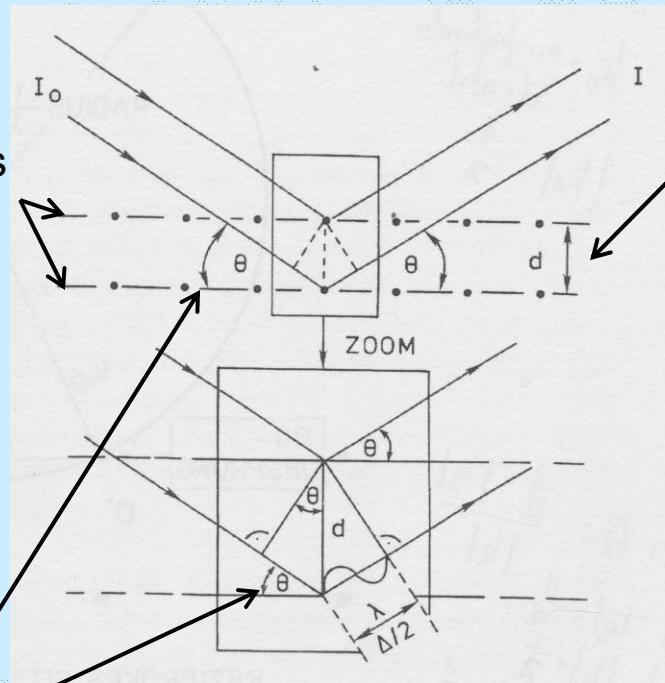
$I$ : intensity of outgoing ray

Face centered cubic (FCC) crystal



Atomic planes of crystal

Each Atom radiates as a "point like" source ("Elastic Scatter")



$d$ : distance between crystal planes

Only constructive interference if path difference equals wavelength! => intensity maximum.

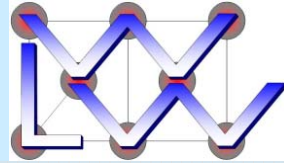
$$n \cdot \lambda = 2 \cdot d \cdot \sin\theta$$

**Bragg equation**

$\theta$ : "Bragg angle"

$\lambda$ : Wavelength

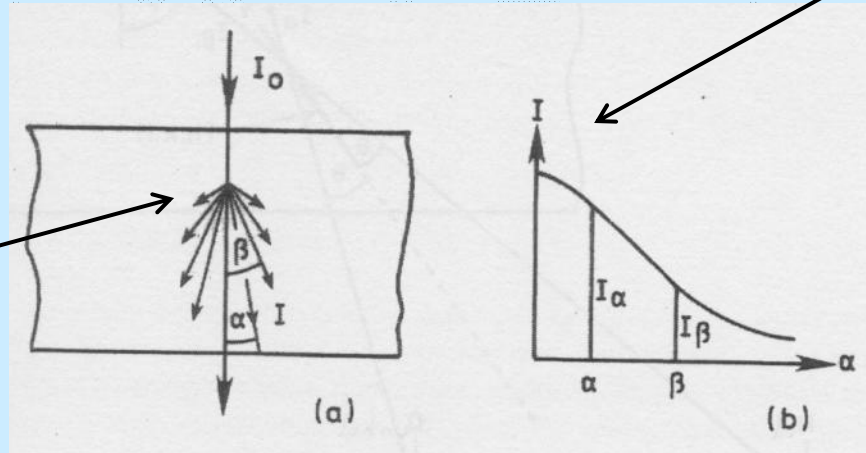
=> For known  $n$ ,  $\lambda$  and  $\theta$  one can calculate  $d$



# Basics for EBSD: Inelastic scatter in thick crystal

Thick crystal:  
=> more and more **inelastic** scatter in every direction!

$I_0$ : intensity of initial ray



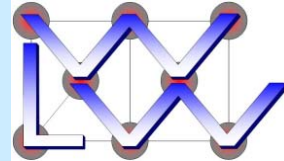
Maximum intensity in initial direction ( $\alpha = 0^\circ$ ), decreasing with increasing angle

$\alpha, \beta$ : diffraction angles

$I$ : intensity of outgoing ray

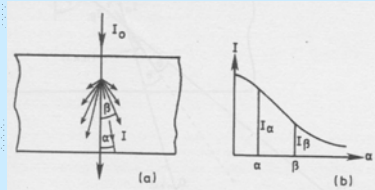
Changes in  $\lambda$  due to energy dissipation negligible

=> new  $I_0$  ray with initial  $\lambda$  but different direction!



Facts:

1)  $I_\alpha > I_\beta$



2) Every crystal plane produces interference **line** (perpendicular to drawing plane) due to ray cones of  $I_\alpha$  and  $I_\beta$

3) crystal plane (almost perpendicular in the crystal) gets hit from both sides

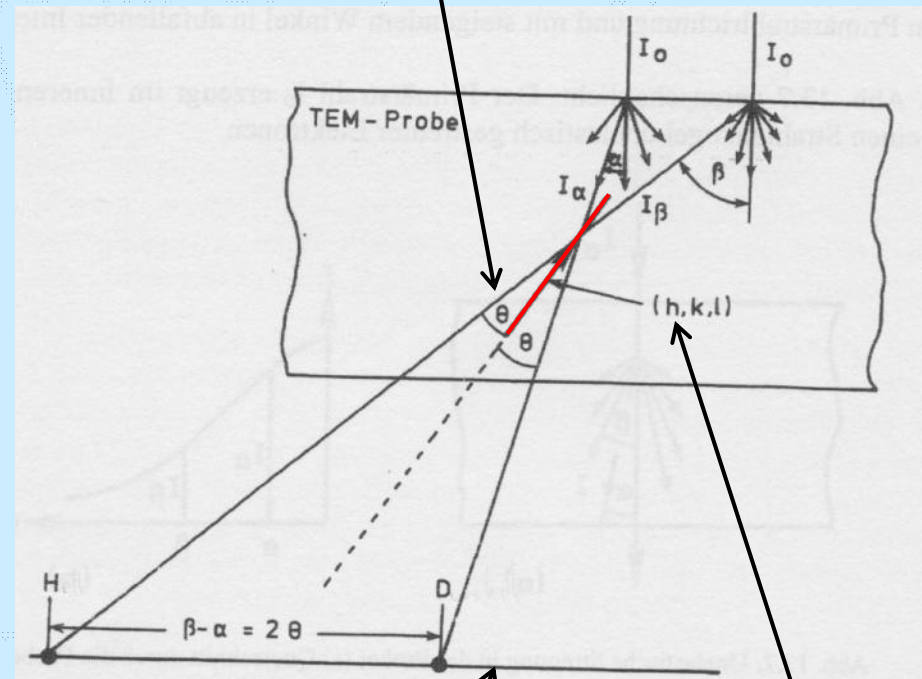
$$f = \frac{\text{scattered intensity}}{\text{primary intensity}}$$

In H: Background +  $\overbrace{(f \cdot I_\alpha - f \cdot I_\beta)}^{> 0} \Rightarrow$  brighter

In D: Background +  $\underbrace{(f \cdot I_\beta - f \cdot I_\alpha)}_{< 0} \Rightarrow$  darker

$\Theta$ : "Bragg angle"

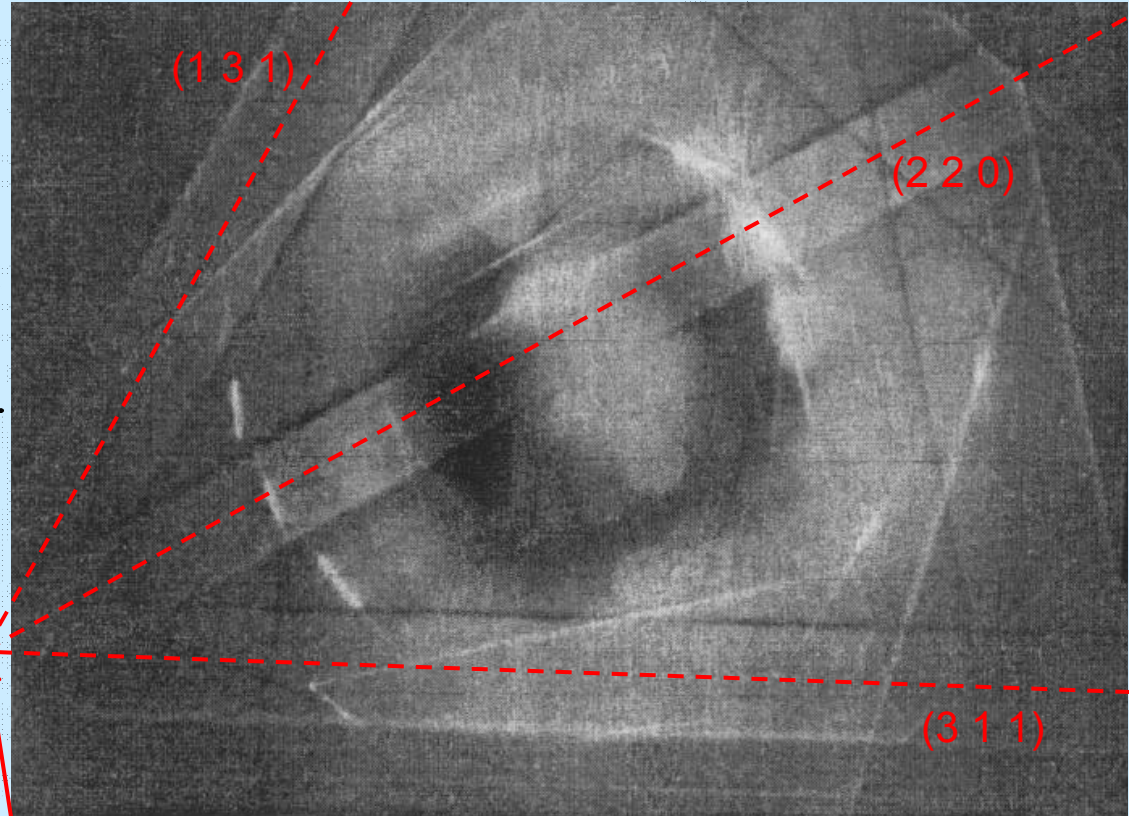
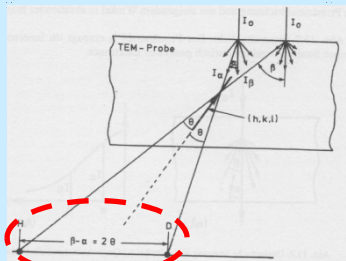
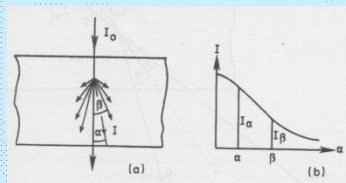
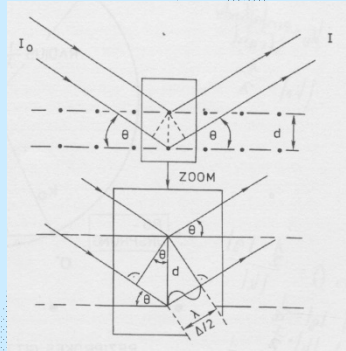
$I_\alpha ; I_\beta$ : intensities of new initial rays



Screen

(h,k,l): crystal plane

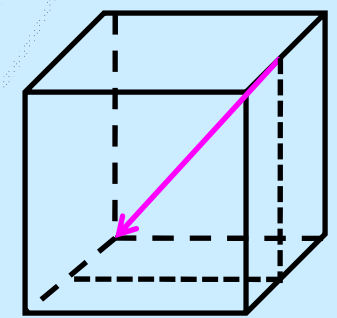
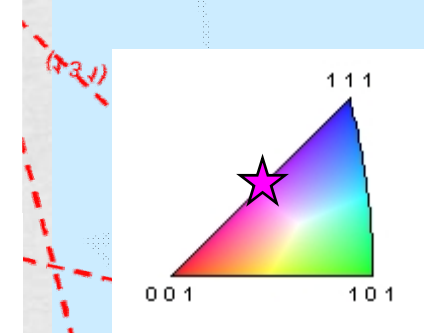
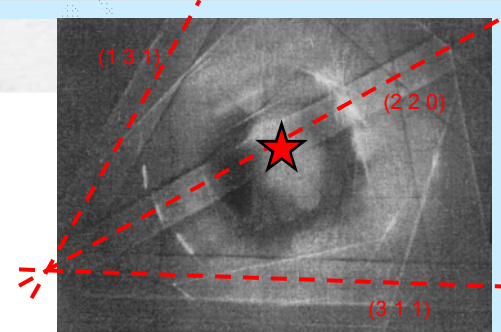
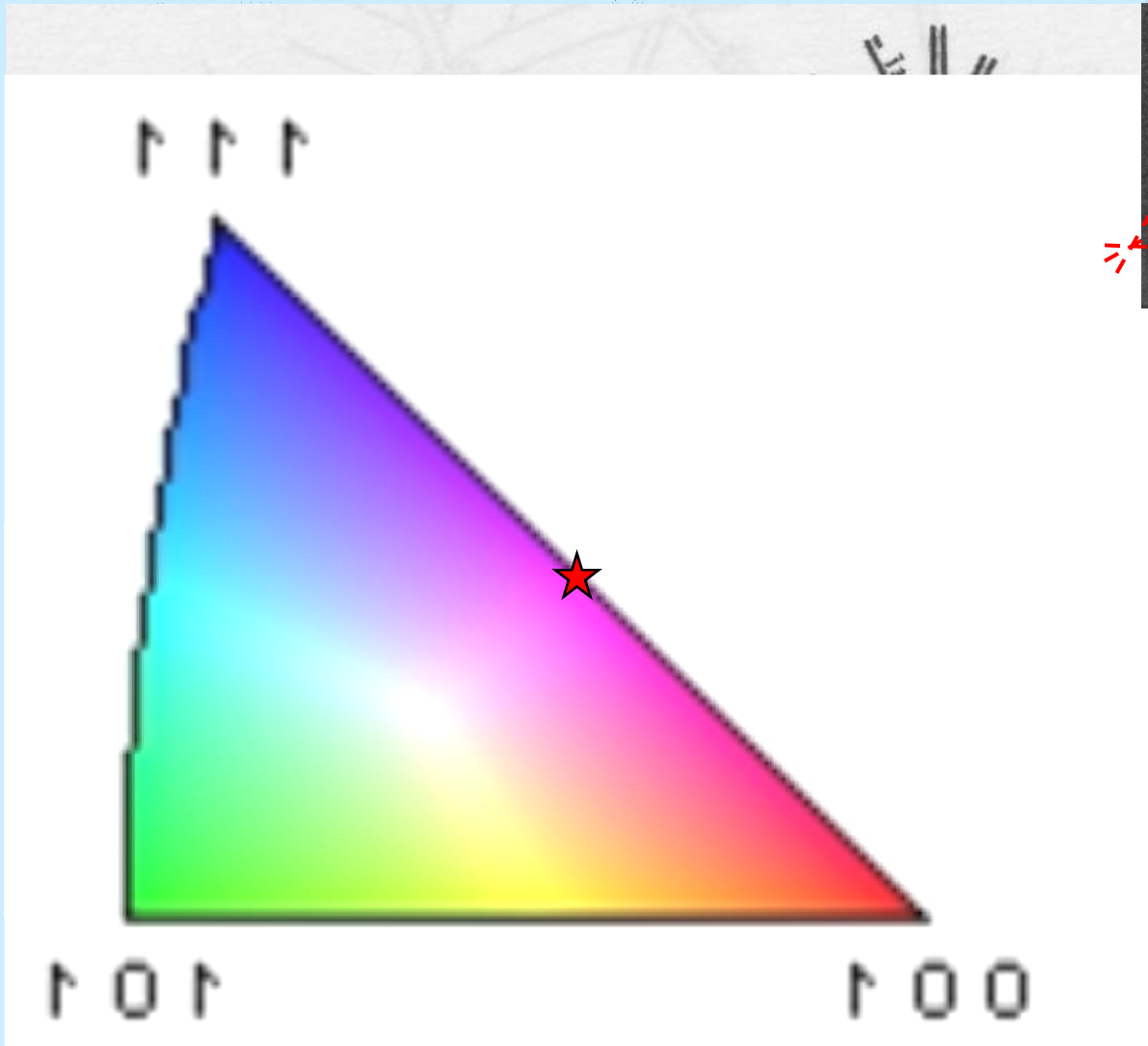
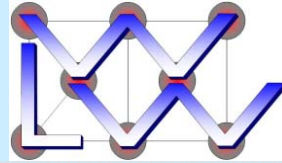
# Basics for EBSD: Kikuchi line



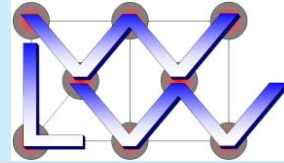
Zone axis  $[-1\ 1\ -2]$

Distance => Bragg equation  
=> planes space  $d$ !  
=> plane identification

# Basics for EBSD: Kikuchi line indexing







Scan:

Each point one Kikuchi pattern

-> each point complete orientation information

=> Mapping of orientations

Scan rate: 75 points/s

Ordinary used for:

- Texture analysis
- Orientation of samples (like X-Ray diffraction but faster)
- Identification of different phases (like TEM but lower resolution/magnification)
- Possibility to connect with quantitative EDX scans

